



# RADIO TEST REPORT

Test Report No. : 11413625S-D-R2

**Applicant** : Sony Corporation  
**Type of Equipment** : AV Receiver  
**Model No.** : XAV-AX100  
**FCC ID** : AK8XAVAX100  
**Test regulation** : FCC Part 15 Subpart C: 2016  
**Test Result** : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. The opinions and the interpretations to the result of the description in this report are outside scopes where UL Japan has been accredited.
6. This test report covers Radio technical requirements. It does not cover administrative issues such as Manual or non-Radio test related Requirements. (if applicable)
7. This report is a revised version of 11413625S-D-R1. 11413625S-D-R1 is replaced with this report.

**Date of test:** August 17 to 30, 2016

**Representative test engineer:**

*H. Morikawa*

Hiroyuki Morikawa  
Engineer  
Consumer Technology Division

**Approved by:**

*A. Hayashi*

Akio Hayashi  
Leader  
Consumer Technology Division



- The testing in which "Non-accreditation" is displayed is outside the accreditation scopes in UL Japan.  
 There is no testing item of "Non-accreditation".

**UL Japan, Inc.**  
**Shonan EMC Lab.**

1-22-3 Megumigaoka, Hiratsuka-shi, Kanagawa-ken, 259-1220 JAPAN  
Telephone : +81 463 50 6400  
Facsimile : +81 463 50 6401

13-EM-F0429



<b>CONTENTS</b>	<b>PAGE</b>
<b>SECTION 1: Customer information.....</b>	<b>4</b>
<b>SECTION 2: Equipment under test (E.U.T.).....</b>	<b>4</b>
<b>SECTION 3: Test specification, procedures &amp; results.....</b>	<b>5</b>
<b>SECTION 4: Operation of E.U.T. during testing.....</b>	<b>8</b>
<b>SECTION 5: Radiated Spurious Emission .....</b>	<b>11</b>
<b>SECTION 6: Antenna Terminal Conducted Tests.....</b>	<b>13</b>
<b>APPENDIX 1: Test data .....</b>	<b>14</b>
20dB Bandwidth and Carrier Frequency Separation.....	14
Number of Hopping Frequency .....	17
Dwell time.....	19
Maximum Peak Output Power .....	22
Average Output Power .....	23
Radiated Spurious Emission .....	24
Conducted Spurious Emission .....	35
Conducted Emission Band Edge compliance .....	41
99%Occupied Bandwidth .....	43
<b>APPENDIX 2: Test instruments .....</b>	<b>45</b>
<b>APPENDIX 3: Photographs of test setup .....</b>	<b>46</b>
Radiated Spurious Emission .....	46

## **SECTION 1: Customer information**

Company Name : Sony Global Manufacturing & Operations Corporation  
Address : 8-4 Shiomi Kisarazu-shi, Chiba, 292-0834 Japan  
Contact Person : Kazuhiko Nagano

## **SECTION 2: Equipment under test (E.U.T.)**

### **2.1 Identification of E.U.T.**

Type of Equipment : AV Receiver  
Model No. : XAV-AX100  
Serial No. : Refer to Section 4, Clause 4.2  
Rating : DC 12 V  
Receipt Date of Sample : August 17, 2016  
Country of Mass-production : China  
Condition of EUT : Production prototype  
(Not for Sale: This sample is equivalent to mass-produced items.)  
Modification of EUT : No Modification by the test lab

### **2.2 Product Description**

Model: XAV-AX100 (referred to as the EUT in this report) is an AV Receiver.

Clock frequency(ies) in the system : 27 MHz, 32 MHz, 26 MHz, 8 MHz, 37.05 MHz

### **Radio Specification**

#### **[Bluetooth]**

Radio Type : Transceiver  
Frequency of Operation : 2402 MHz - 2480 MHz  
Modulation : FHSS  
Power Supply (radio part input) : DC 3.3 V  
Antenna type : 2.4 G wire Antenna  
Antenna Gain : Peak 1.68 dBi, Average 1.1 dBi

## **SECTION 3: Test specification, procedures & results**

### **3.1 Test Specification**

Test Specification : FCC Part 15 Subpart C  
FCC part 15 final revised on April 6, 2016.

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators  
Section 15.207 Conducted limits  
Section 15.247 Operation within the bands 902-928MHz,  
2400-2483.5MHz, and 5725-5850MHz

\* Also the EUT complies with FCC Part 15 Subpart B.

### **3.2 Procedures and results**

Item	Test Procedure	Specification	Worst Margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.10-2013 6. Standard test methods IC: RSS-Gen 8.8	FCC: Section 15.207 ----- IC: RSS-Gen 8.8	N/A	N/A	*1)
Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) ----- IC: RSS-247 5.1 (2)	See data.	Complied	Conducted
20dB Bandwidth	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) ----- IC: RSS-247 5.1 (1)		Complied	Conducted
Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) ----- IC: RSS-247 5.1 (4)		Complied	Conducted
Dwell time	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) ----- IC: RSS-247 5.1 (4)		Complied	Conducted
Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 6.12	FCC: Section15.247(a)(b)(1) ----- IC: RSS-247 5.4 (2)		Complied	Conducted
Spurious Emission & Band Edge Compliance	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 6.13	FCC: Section15.247(d) ----- IC: RSS-247 5.5 RSS-Gen 8.9 RSS-Gen 8.10	1.0 dB 144.000 MHz, QP, Hori. Tx, Hopping Off, DH5 2480 MHz	Complied	Conducted/ Radiated (above 30 MHz) *2)

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

\*1) The test is not applicable since the EUT has no AC mains.

\*2) Radiated test was selected over 30 MHz based on section 15.247(d).

\* In case any questions arise about test procedure, ANSI C63.10: 2013 is also referred.

#### **FCC Part 15.31 (e)**

The equipment provides the wireless transmitter with stable power supply (DC 3.3 V). Instead of a new battery, DC power supply was used for the test. That does not affect the test result, therefore the EUT complies with the requirement.

#### **FCC Part 15.203 Antenna requirement**

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

**UL Japan, Inc.**

**Shonan EMC Lab.**

1-22-3 Megumigaoka, Hiratsuka-shi, Kanagawa-ken, 259-1220 JAPAN

Telephone : +81 463 50 6400

Facsimile : +81 463 50 6401

### 3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Bandwidth	IC: RSS-Gen 6.6	IC: -	N/A	-	Conducted

Other than above, no addition, exclusion nor deviation has been made from the standard.

### 3.4 Uncertainty

#### EMI

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor  $k = 2$ .  
Shonan EMC Lab.

Item	Frequency range	Uncertainty (+/-)			
		No. 1 SAC / SR	No. 2 SAC / SR	No. 3 SAC / SR	No. 4 SAC / SR
Conducted emission (AC Mains) LISN	150 kHz-30 MHz	2.1 dB	2.1 dB	2.6 dB	2.2 dB
Radiated emission (Measurement distance: 3 m)	9 kHz-30 MHz	2.7 dB	2.7 dB	3.1 dB	-
	30 MHz-300 MHz	4.4 dB	4.4 dB	4.6 dB	-
	300 MHz-1 GHz	5.6 dB	5.5 dB	5.3 dB	-
	1 GHz-13 GHz	5.2 dB	5.2 dB	5.2 dB	-
Radiated emission (Measurement distance: 1 m)	13 GHz-18 GHz	4.9 dB	4.9 dB	4.9 dB	-
	18 GHz-40 GHz	4.9 dB	4.9 dB	4.9 dB	-

SAC=Semi-Anechoic Chamber

SR= Shielded Room is applied besides radiated emission

Antenna terminal test	Uncertainty (+/-)
Power Measurement above 1 GHz (Average Detector)_SPM-06	0.76 dB
Power Measurement above 1 GHz (Peak Detector)_SPM-06	0.79 dB
Power Measurement above 1 GHz (Average Detector)_SPM-07	0.74 dB
Power Measurement above 1 GHz (Peak Detector)_SPM-07	1.08 dB
Spurious emission (Conducted) below 1GHz	1.5 dB
Spurious emission (Conducted) 1 GHz-3 GHz	1.7 dB
Spurious emission (Conducted) 3 GHz-18 GHz	2.4 dB
Spurious emission (Conducted) 18 GHz-26.5 GHz	2.5 dB
Spurious emission (Conducted) 26.5 GHz-40 GHz	2.5 dB
Bandwidth Measurement	0.66 %
Duty cycle and Time Measurement	0.012 %

#### Radiated emission test

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

### 3.5 Test Location

UL Japan, Inc. Shonan EMC Lab.  
1-22-3, Megumigaoka, Hiratsuka-shi, Kanagawa-ken 259-1220 JAPAN  
Telephone: +81 463 50 6400, Facsimile: +81 463 50 6401  
JAB Accreditation No. RTL02610

Test site	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Maximum measurement distance
No.1 Semi-anechoic chamber	2973D-1	20.6 x 11.3 x 7.65	20.6 x 11.3	10m
No.2 Semi-anechoic chamber	2973D-2	20.6 x 11.3 x 7.65	20.6 x 11.3	10m
No.3 Semi-anechoic chamber	2973D-3	12.7 x 7.7 x 5.35	12.7 x 7.7	5m
No.4 Semi-anechoic chamber	-	8.1 x 5.1 x 3.55	8.1 x 5.1	-
No.1 Shielded room	-	6.8 x 4.1 x 2.7	6.8 x 4.1	-
No.2 Shielded room	-	6.8 x 4.1 x 2.7	6.8 x 4.1	-
No.3 Shielded room	-	6.3 x 4.7 x 2.7	6.3 x 4.7	-
No.4 Shielded room	-	4.4 x 4.7 x 2.7	4.4 x 4.7	-
No.5 Shielded room	-	7.8 x 6.4 x 2.7	7.8 x 6.4	-
No.6 Shielded room	-	7.8 x 6.4 x 2.7	7.8 x 6.4	-
No.8 shielded room	-	3.45 x 5.5 x 2.4	3.45 x 5.5	-
No.1 Measurement room	-	2.55 x 4.1 x 2.5	-	-

### 3.6 Test data, Test instruments, and Test set up

Refer to APPENDIX.

## **SECTION 4: Operation of E.U.T. during testing**

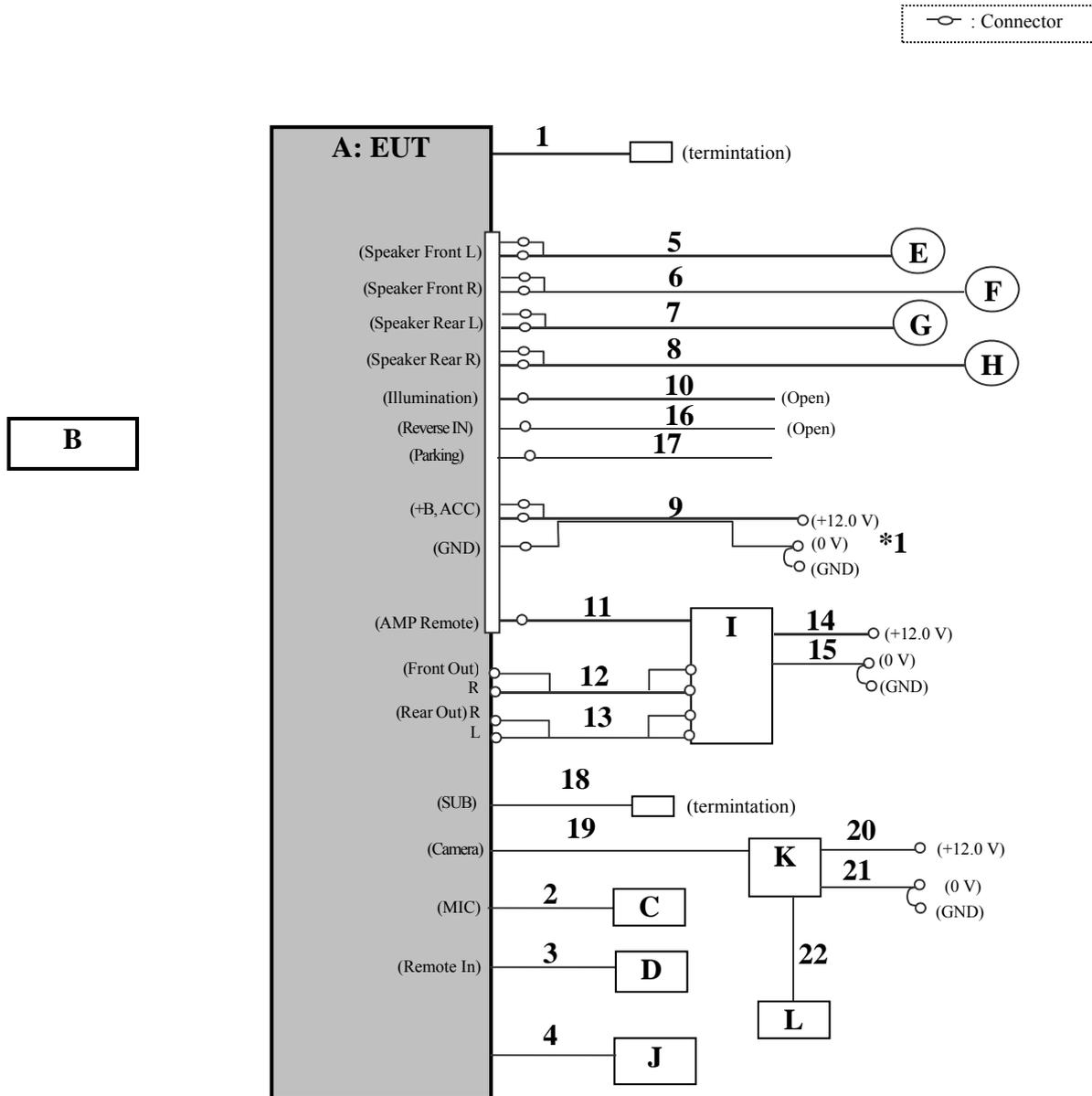
### **4.1 Operating Mode(s)**

Bluetooth (BT): Transmitting (Tx), Payload: PRBS9

Details of Operating Mode(s)

<b>Test Item</b>	<b>Mode</b>	<b>Tested frequency</b>
Spurious Emission (Conducted/Radiated)	Tx (Hopping Off) DH5, 3DH5	2402 MHz 2441 MHz 2480 MHz
Carrier Frequency Separation	Tx (Hopping On) DH5, 3DH5	2402 MHz 2441 MHz 2480 MHz
20dB Bandwidth	Tx (Hopping Off) DH5, 3DH5	2402 MHz 2441 MHz 2480 MHz
Number of Hopping Frequency	Tx (Hopping On) DH5, 3DH5	-
Dwell time	Tx (Hopping On), -DH1, DH3, DH5 -3DH1, 3DH3, 3DH5	-
Maximum Peak Output Power	Tx (Hopping Off) DH5, 2DH5, 3DH5	2402 MHz 2441 MHz 2480 MHz
Band Edge Compliance (Conducted)	Tx DH5, 3DH5 -Hopping On -Hopping Off	2402 MHz 2480 MHz
99% Occupied Bandwidth	Tx DH5, 3DH5 -Hopping On -Hopping Off	2402 MHz 2441 MHz 2480 MHz
<p>*As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload length (except Dwell time test)</p> <p>*2DH mode (2Mb/s EDR: pi/4DQPSK) was excluded for other tests than power measurement by using 3DH mode (3 Mb/s EDR: 8DPSK) as a representative.</p> <p>* It is considered that the non-tested packet type (e.g. inquiry) can be omitted as it is complied with above all the test items based on Bluetooth Core specification.</p> <p>*EUT has the power settings by the software as follows;  Power settings: Fixed  Software: RDA Host Controller Data Transfer Tester Application  *This setting of software is the worst case.  Any conditions under the normal use do not exceed the condition of setting.  In addition, end users cannot change the settings of the output power of the product.</p>		

## 4.2 Configuration and peripherals



\* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

**Description of EUT and Support equipment**

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	AV Receiver	XAV-AX100	0000U-9 *1) 0000U-8 *2)	Sony	EUT
B	Remote Commander	RM-X170	-	Sony	-
C	MIC	-	-	Sony	-
D	Wired Remote Controller	RM-X2S	-	Sony	-
E	Speaker 1	IS-10	-	Sony	-
F	Speaker 2	IS-10	-	Sony	-
G	Speaker 3	XS-GTF1625R	-	Sony	-
H	Speaker 4	XS-GTF1625R	-	Sony	-
I	Stereo Power Amplifier	XM-4S-020	S0C5	Sony	-
J	USB Memory	SDK-USM4GL(B)	10615MEDB	Sony	-
K	Rear View Camera	XA-R800C	100114	Sony	-
L	Camera	-	-	Sony	-

\*1) Used for Antenna Terminal conducted test

\*2) Used for Conducted Emission test and Radiated Emission test

**List of cables used**

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	FM antenna	1.1	Shielded	Shielded	-
2	MIC	3.0	Shielded	Shielded	-
3	REMOTE IN	2.0	Shielded	Shielded	-
4	USB	0.2+1.35	Shielded	Shielded	-
5	Speaker (1)	0.15+2.1	Unshielded	Unshielded	-
6	Speaker (2)	0.15+2.1	Unshielded	Unshielded	-
7	Speaker (3)	0.15+2.1	Unshielded	Unshielded	-
8	Speaker (4)	0.15+2.1	Unshielded	Unshielded	-
9	DC Power	0.15+2.1	Unshielded	Unshielded	-
10	Illumination	0.15+1.5	Unshielded	Unshielded	-
11	AMP Remote	0.15+1.4	Unshielded	Unshielded	-
12	RCA (Front Audio Out)	5.0	Shielded	Shielded	-
13	RCA (Rear Audio Out)	5.0	Shielded	Shielded	-
14	DC Power (+)	1.3	Unshielded	Unshielded	-
15	DC Power (-)	1.3	Unshielded	Unshielded	-
16	Reverse In	0.15+1.5	Unshielded	Unshielded	-
17	Parking	1.9	Unshielded	Unshielded	-
18	Video	2.0	Shielded	Shielded	-
19	Video	2.0	Shielded	Shielded	-
20	DC Power (+)	1.3	Unshielded	Unshielded	-
21	DC Power (-)	1.3	Unshielded	Unshielded	-
22	Camera	3.0	Shielded	Shielded	-

**UL Japan, Inc.**

**Shonan EMC Lab.**

1-22-3 Megumigaoka, Hiratsuka-shi, Kanagawa-ken, 259-1220 JAPAN

Telephone : +81 463 50 6400

Facsimile : +81 463 50 6401

## **SECTION 5: Radiated Spurious Emission**

### **Test Procedure**

[For below 1 GHz]

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

[For above 1 GHz]

EUT was placed on a urethane platform of nominal size, 0.5 m by 0.5 m, raised 1.5 m above the conducting ground plane.

The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with absorbent materials lined on a ground plane.

The height of the measuring antenna varied between 1 and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

### **Test Antennas are used as below;**

Frequency	30 MHz to 300 MHz	300 MHz to 1 GHz	Above 1 GHz
Antenna Type	Biconical	Logperiodic	Horn

In any 100 kHz bandwidth outside the restricted band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

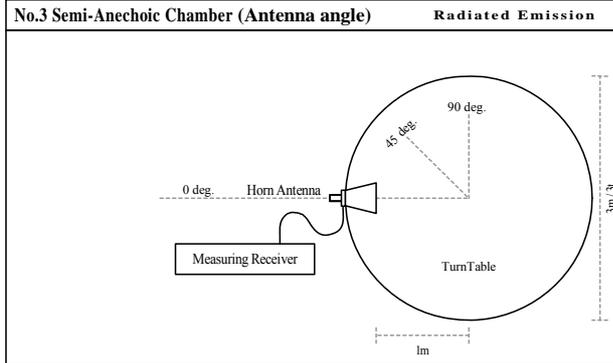
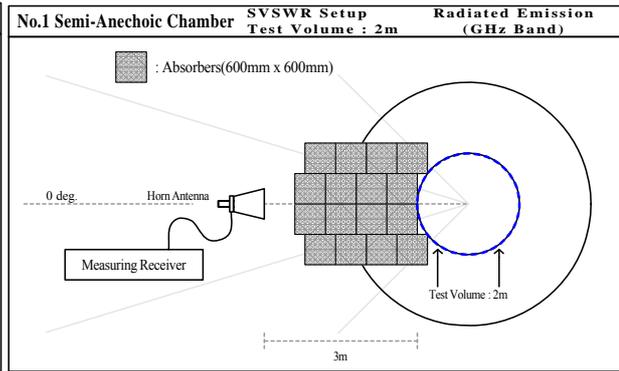
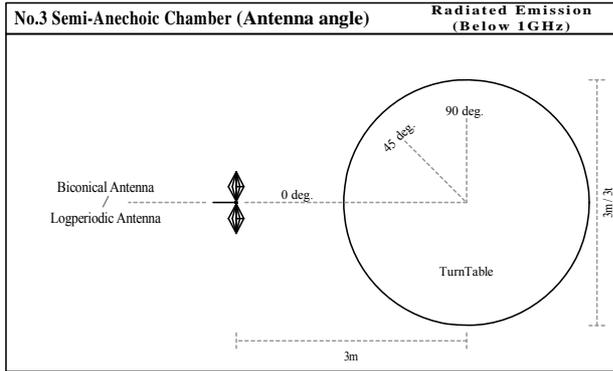
### **20 dBc was applied to the frequency over the limit of FCC 15.209 / Table 4 of RSS-Gen 8.9 (IC) and outside the restricted band of FCC15.205 / Table 6 of RSS-Gen 8.10 (IC).**

Frequency	Below 1 GHz	Above 1 GHz		20 dBc
Instrument used	Test Receiver	Spectrum Analyzer		Spectrum Analyzer
Detector	QP	PK	AV	PK
IF Bandwidth	BW 120 kHz	RBW: 1 MHz VBW: 3 MHz	RBW: 1 MHz VBW: 10 Hz *1)	RBW: 100 kHz VBW: 300 kHz
Test Distance	3 m	3 m*2) (1 GHz – 13 GHz), 1 m*3) (13 GHz – 26.5 GHz)		3 m*2) (1 GHz – 13 GHz), 1 m*3) (13 GHz – 26.5 GHz)

\*1) Although DA 00-705 accepts VBW = 10 Hz for AV measurements, it was confirmed that superfluous smoothing was not performed.

\*2) Distance Factor:  $20 \times \log(3.88 \text{ m}/3.0 \text{ m}) = 2.24 \text{ dB}$

\*3) Distance Factor:  $20 \times \log(1.0 \text{ m}/3.0 \text{ m}) = -9.5 \text{ dB}$



- The carrier level and noise levels were confirmed at angle of -45 deg. to +45 deg. based on the product specification to see the position of maximum noise, and the test was made at the position (below 1 GHz: 0 deg., above 1 GHz: +45 deg.)

The test results and limit are rounded off to one decimal place, so some differences might be observed.

**Measurement range** : 30 MHz - 26.5 GHz  
**Test data** : APPENDIX  
**Test result** : Pass

## **SECTION 6: Antenna Terminal Conducted Tests**

### **Test Procedure**

The tests were made with below setting connected to the antenna port.

<b>Test</b>	<b>Span</b>	<b>RBW</b>	<b>VBW</b>	<b>Sweep time</b>	<b>Detector</b>	<b>Trace</b>	<b>Instrument used</b>
20dB Bandwidth	3 MHz	30 kHz	100 kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth *1)	Enough width to display emission skirts	1 to 5 % of OBW	Three times of RBW	Auto	Peak	Max Hold *1)	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Auto	Peak Average *3)	-	Power Meter (Sensor: 50MHz BW)
Carrier Frequency Separation	3 MHz	100 kHz	300 kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Number of Hopping Frequency	30 MHz	300 kHz	1 MHz	Auto	Peak	Max Hold	Spectrum Analyzer
Dwell Time	Zero Span	100 kHz, 1 MHz	300 kHz, 3 MHz	As necessary capture the entire dwell time per hopping channel	Peak	Clear Write	Spectrum Analyzer
Conducted Spurious Emission *2)	9 kHz to 150 kHz	200 Hz	620 Hz	Auto	Peak	Max Hold	Spectrum Analyzer
	150 kHz to 30 MHz	9.1 kHz	27 kHz				
	30 MHz to 25 GHz	100 kHz	300 kHz				
Conducted Spurious Emission Band Edge compliance	10 MHz	100 kHz	300 kHz	Auto	Peak	Max Hold	Spectrum Analyzer

\*1) The measurement was performed with Max Hold since the duty cycle was not 100 %.

\*2) In the frequency range below 30MHz, RBW was narrowed to separate the noise contents.

Then, wide-band noise near the limit was checked separately, however the noise was low enough as shown in the chart.

(9 kHz - 150 kHz: RBW = 200Hz, 150 kHz - 30 MHz: RBW = 10 kHz).

\*3) Reference data

The test results and limit are rounded off to two decimals place, so some differences might be observed.

**Test data : APPENDIX**

**Test result : Pass**

## APPENDIX 1: Test data

### 20dB Bandwidth and Carrier Frequency Separation

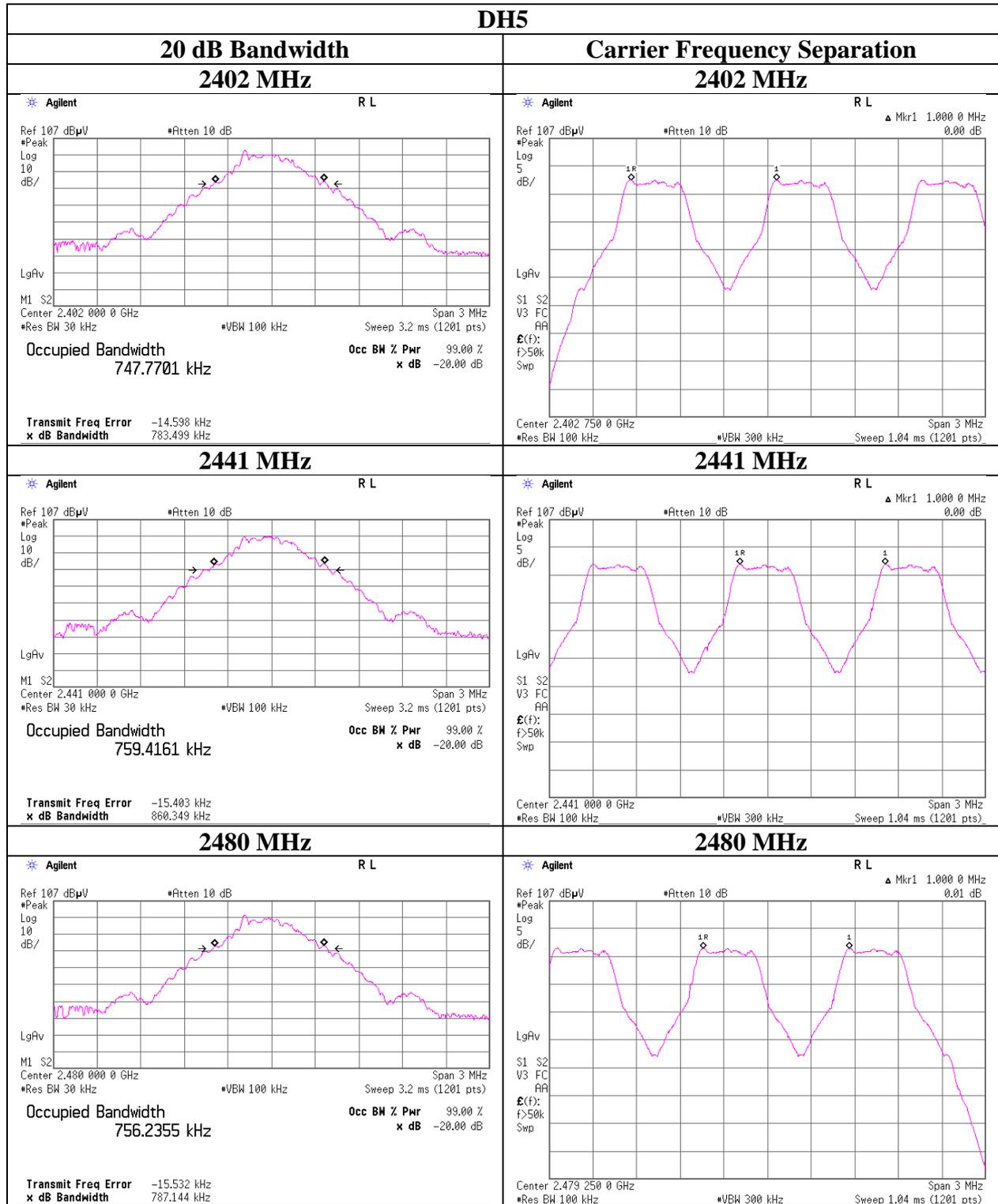
Test place                      Shonan EMC Lab. No.3 Shielded Room  
Report No.                      11413625S-D-R2  
Date                              August 22, 2016  
Temperature / Humidity        24 deg. C / 52 % RH  
Engineer                        Kazutaka Takeyama  
Mode                              Tx, Hopping Off

Mode	Freq. [MHz]	20dB Bandwidth [MHz]	Carrier Frequency Separation [MHz]	Limit for Carrier Frequency separation [MHz]
DH5	2402.0	0.783	1.000	$\geq 0.522$
DH5	2441.0	0.860	1.000	$\geq 0.574$
DH5	2480.0	0.787	1.000	$\geq 0.525$
3DH5	2402.0	1.154	1.000	$\geq 0.769$
3DH5	2441.0	1.099	1.000	$\geq 0.732$
3DH5	2480.0	1.120	1.000	$\geq 0.747$

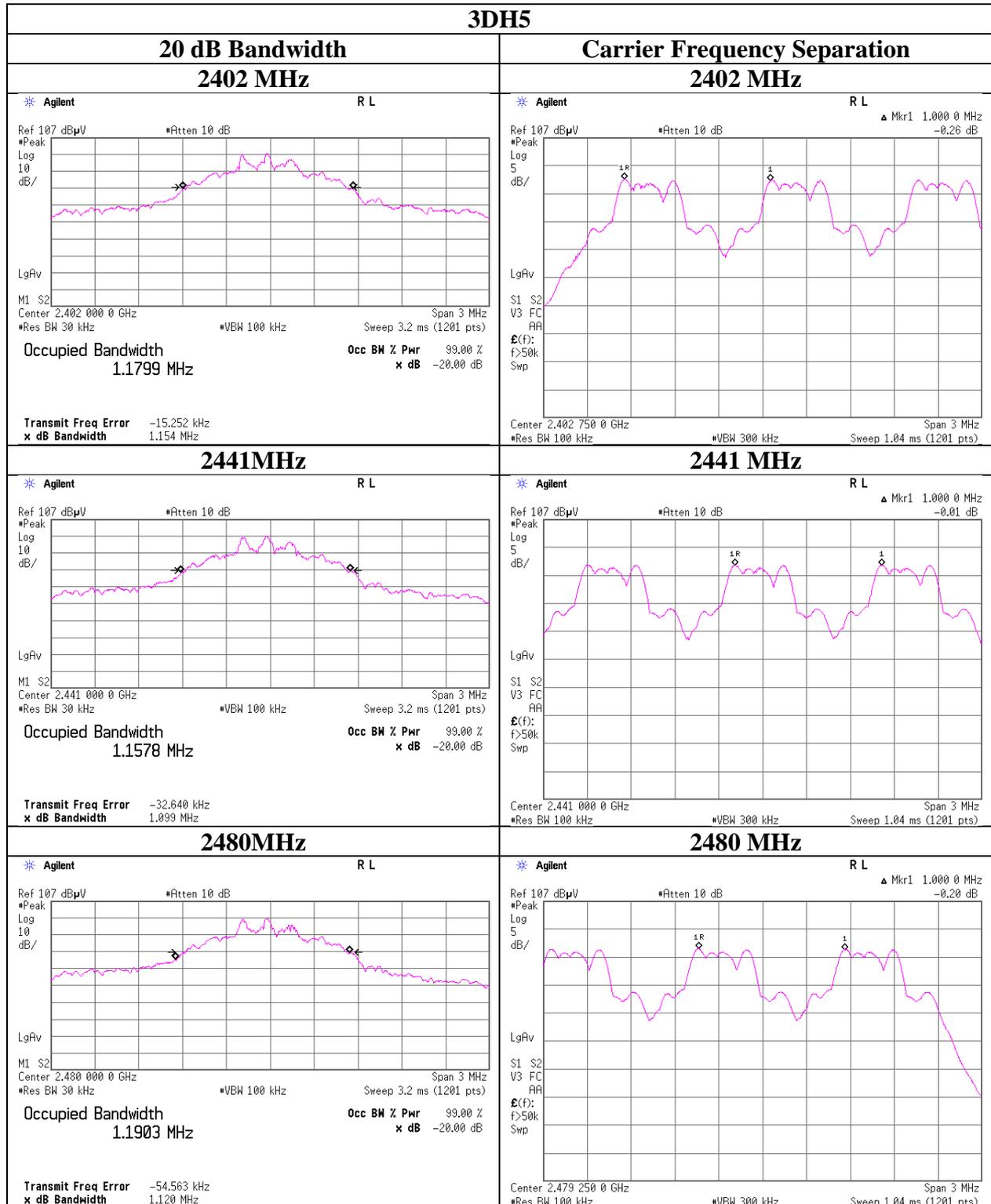
Limit: Two-thirds of 20dB Bandwidth or 25kHz (whichever is greater).

No limit applies to 20dB Bandwidth.

## 20dB Bandwidth and Carrier Frequency Separation



## 20dB Bandwidth and Carrier Frequency Separation



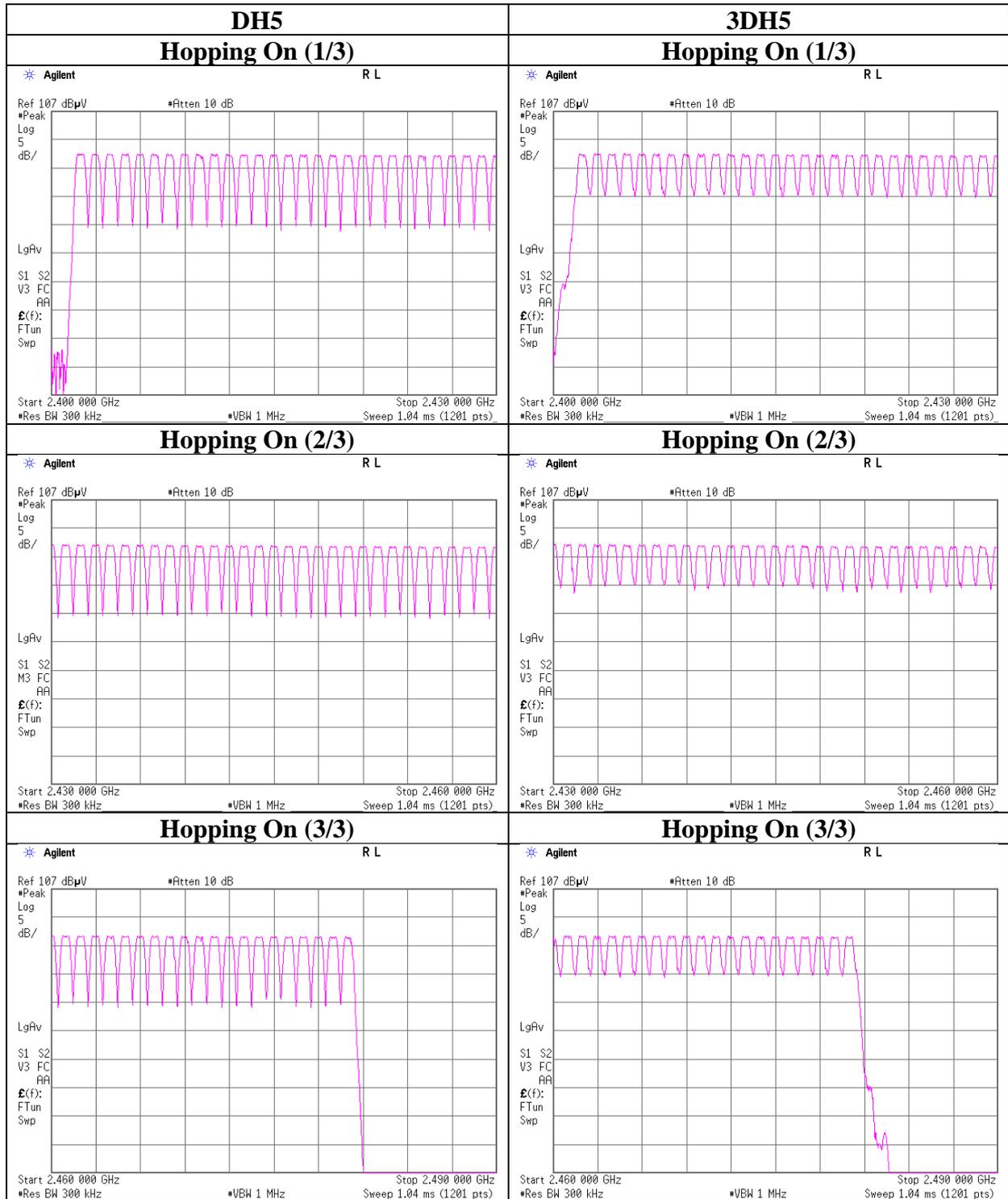
### Number of Hopping Frequency

Test place Shonan EMC Lab. No.3 Shielded Room  
Report No. 11413625S-D-R2  
Date August 22, 2016  
Temperature / Humidity 24 deg. C / 52 % RH  
Engineer Kazutaka Takeyama  
Mode Tx, Hopping On

Mode	Number of channel [channels]	Limit [channels]
DH5	79	$\geq 15$
3DH5	79	$\geq 15$

Test was not performed at AFH mode whose number of hopping channel is 20 channels because this Bluetooth radio is in compliance of Bluetooth Specification.

### Number of Hopping Frequency



## Dwell time

Test place : Shonan EMC Lab. No.4 Shielded Room  
Report No. : 11413625S-D-R2  
Date : August 30, 2016  
Temperature / Humidity : 25 deg. C / 68 % RH  
Engineer : Hiroyuki Morikawa  
Mode : Tx, Hopping On

Mode	Number of transmission in a 31.6(79 Hopping x 0.4) / 12.8 (32 Hopping x 0.4) second period			Length of transmission [msec]	Result [msec]	Limit [msec]
	51.0 times / 5 sec.	x	31.6 sec. =			
DH1	51.0 times / 5 sec.	x	31.6 sec. =	0.417	135	400
DH3	26.0 times / 5 sec.	x	31.6 sec. =	1.689	279	400
DH5	17.0 times / 5 sec.	x	31.6 sec. =	2.937	317	400
3DH1	51.0 times / 5 sec.	x	31.6 sec. =	0.417	135	400
3DH3	26.0 times / 5 sec.	x	31.6 sec. =	1.680	277	400
3DH5	17.0 times / 5 sec.	x	31.6 sec. =	2.943	318	400

Sample Calculation

Result = Number of transmission x Length of transmission

\*Average data of 5 tests.(except Inquiry)

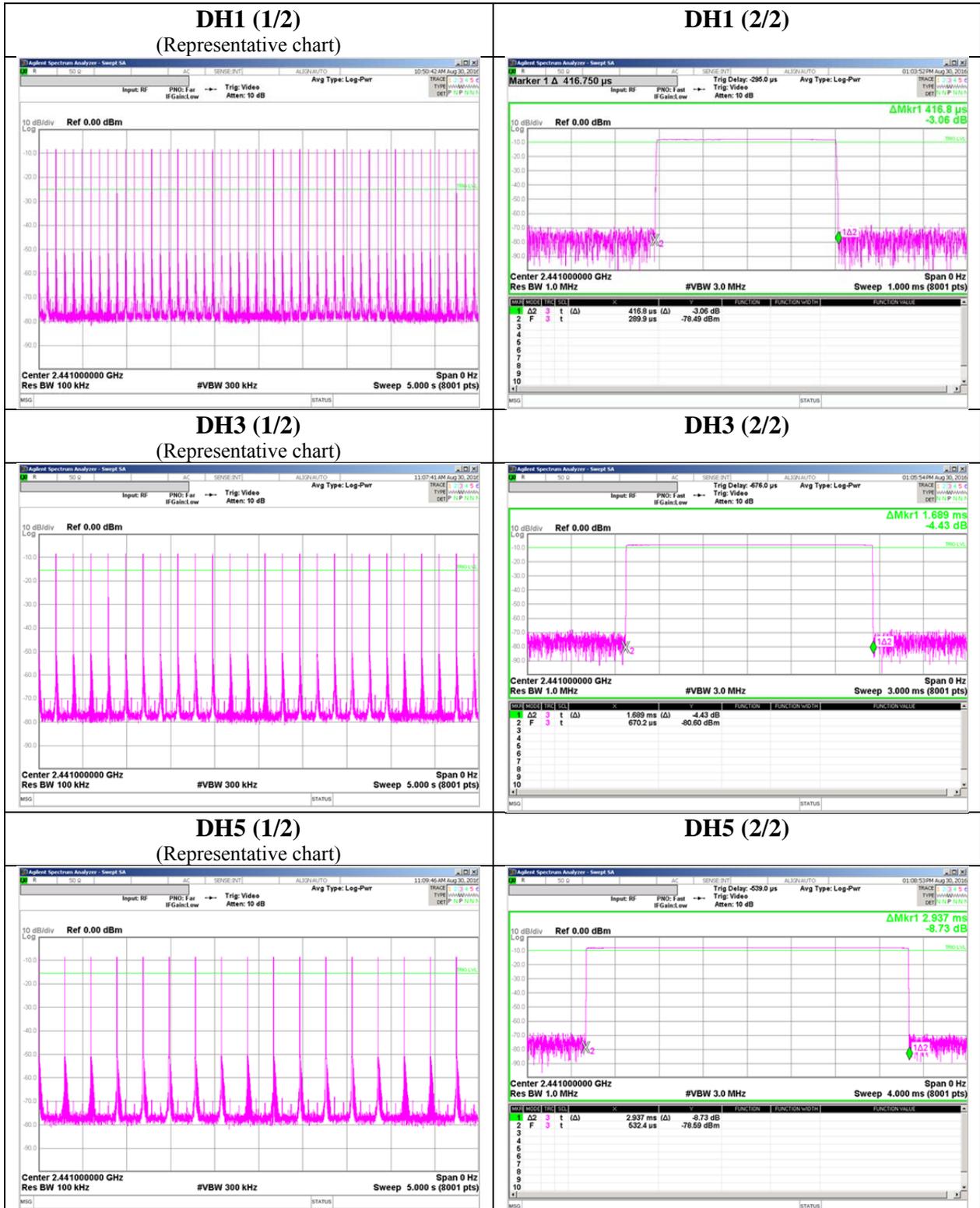
Mode	Sampling [times]					Average [times]
	1	2	3	4	5	
DH1	51	51	51	51	51	51
DH3	26	26	26	26	26	26
DH5	17	17	17	17	17	17
3DH1	51	51	51	51	51	51
3DH3	26	26	26	26	26	26
3DH5	17	17	17	17	17	17

Sample Calculation

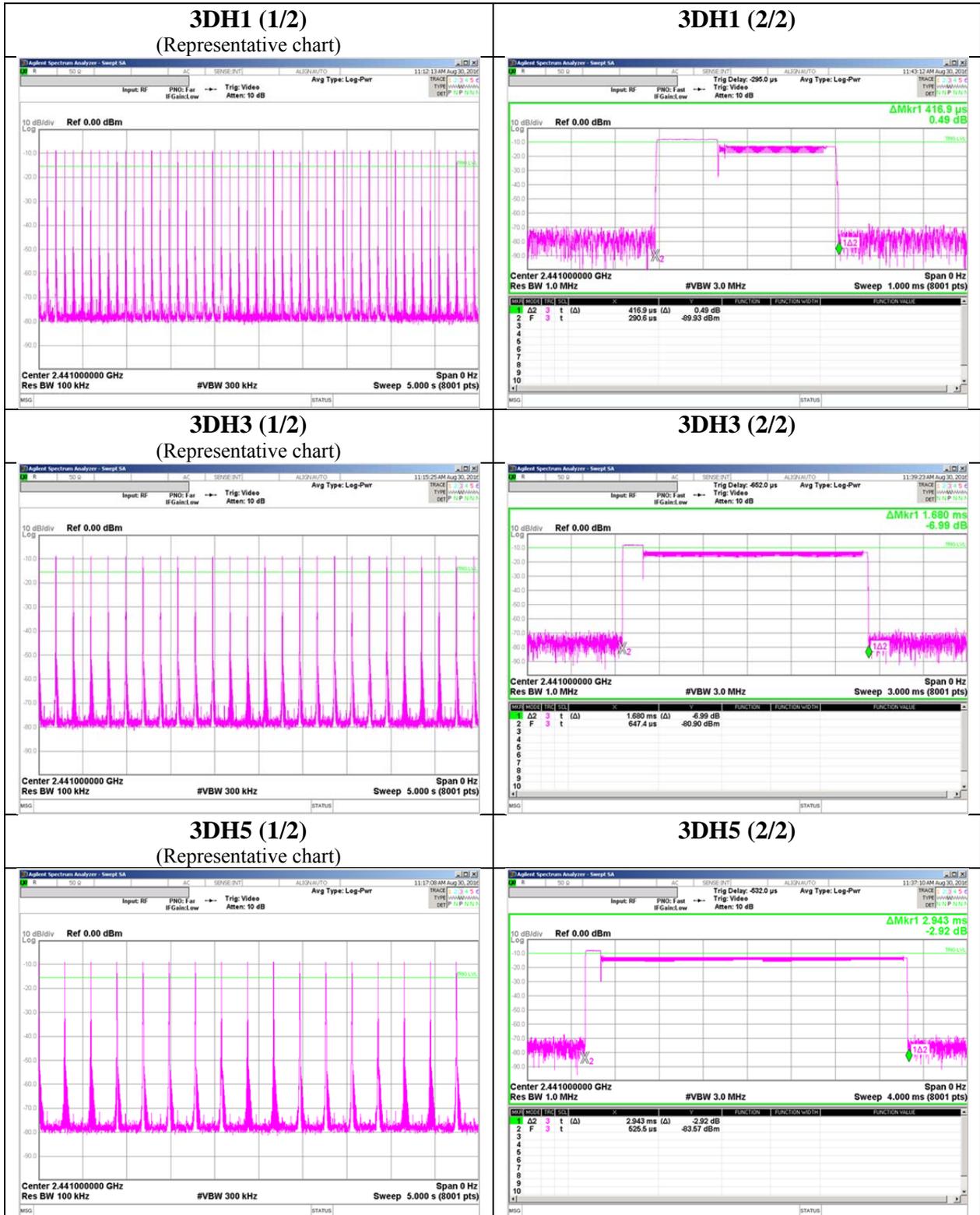
Average = Summation (Sampling 1 to 5) / 5

This device complies with the Bluetooth protocol for FHSS operation, employing a pseudo random channel selection and hopping rate to ensure that the occupancy time in  $N \times 0.4s$ , where  $N$  is the number of channels being used in the hopping sequence ( $20 \leq N \leq 79$ ), is always less than  $0.4s$  regardless of packet size. This is confirmed in the test report for  $N = 79$ .

## Dwell time



### Dwell time



## Maximum Peak Output Power

Test place : Shonan EMC Lab. No.3 Shielded Room  
Report No. : 11413625S-D-R2  
Date : August 22, 2016  
Temperature / Humidity : 24 deg. C / 52 % RH  
Engineer : Kazutaka Takeyama  
Mode : Tx, Hopping Off

Mode	Freq. [MHz]	Reading [dBm]	Cable Loss [dB]	Atten. Loss [dB]	Result		Limit		Margin [dB]
					[dBm]	[mW]	[dBm]	[mW]	
DH5	2402.0	-7.40	1.08	10.01	3.69	2.34	20.96	125	17.27
DH5	2441.0	-7.92	1.09	10.01	3.18	2.08	20.96	125	17.78
DH5	2480.0	-8.35	1.11	10.01	2.77	1.89	20.96	125	18.19
2DH5	2402.0	-7.42	1.08	10.01	3.67	2.33	20.96	125	17.29
2DH5	2441.0	-8.00	1.09	10.01	3.10	2.04	20.96	125	17.86
2DH5	2480.0	-8.41	1.11	10.01	2.71	1.87	20.96	125	18.25
3DH5	2402.0	-7.38	1.08	10.01	3.71	2.35	20.96	125	17.25
3DH5	2441.0	-7.95	1.09	10.01	3.15	2.07	20.96	125	17.81
3DH5	2480.0	-8.37	1.11	10.01	2.75	1.88	20.96	125	18.21

Sample Calculation:

Result = Reading + Cable Loss (including the cable(s) customer supplied) + Attenuator Loss

\*The equipment and cables were not used for factor 0 dB of the data sheets.

Test was not performed at AFH mode, because the decrease of number of channel (min: 20ch) at AFH mode does not influence on the output power and bandwidth of the EUT.

As this device had AFH mode and frequency separation could not meet the requirement of over 20dB BW without 2/3 relaxation, 125mW power limit was applied to it.

**Average Output Power**  
**(Reference data for RF Exposure)**

Test place : Shonan EMC Lab. No.3 Shielded Room  
Report No. : 11413625S-D-R2  
Date : August 22, 2016  
Temperature / Humidity : 24 deg. C / 52 % RH  
Engineer : Kazutaka Takeyama  
Mode : Tx, Hopping Off

Mode	Freq. [MHz]	Reading [dBm]	Cable Loss [dB]	Atten. Loss [dB]	Result (Time average)		Duty factor [dB]	Result (Burst power average)	
					[dBm]	[mW]		[dBm]	[mW]
DH5	2402.0	-8.65	1.08	10.01	2.44	1.75	1.05	3.49	2.23
DH5	2441.0	-9.21	1.09	10.01	1.89	1.55	1.05	2.94	1.97
DH5	2480.0	-9.64	1.11	10.01	1.48	1.41	1.05	2.53	1.79
2DH5	2402.0	-13.73	1.08	10.01	-2.64	0.54	1.06	-1.58	0.70
2DH5	2441.0	-14.11	1.09	10.01	-3.01	0.50	1.06	-1.95	0.64
2DH5	2480.0	-14.33	1.11	10.01	-3.21	0.48	1.06	-2.15	0.61
3DH5	2402.0	-13.70	1.08	10.01	-2.61	0.55	1.06	-1.55	0.70
3DH5	2441.0	-14.08	1.09	10.01	-2.98	0.50	1.06	-1.92	0.64
3DH5	2480.0	-14.29	1.11	10.01	-3.17	0.48	1.06	-2.11	0.62

Sample Calculation:

Result (Time average) = Reading + Cable Loss (including the cable(s) customer supplied) + Attenuator Loss

Result (Burst power average) = Time average + Duty factor

\*The equipment and cables were not used for factor 0 dB of the data sheets.

## Radiated Spurious Emission

Test place : Shonan EMC Lab. No.1 and No.3 Semi Anechoic Chamber  
Report No. : 11413625S-D-R2  
Date : August 17, 2016 August 18, 2016  
Temperature / Humidity : 23 deg. C / 58 % RH 22 deg. C / 61 % RH  
Engineer : Takahiro Suzuki Takahiro Suzuki  
(1-18 GHz) (30-1000 MHz)  
(No.1SAC) (18-26.5GHz)  
(No.1SAC)  
Mode : Tx, Hopping Off, DH5 2402 MHz

(\* PK: Peak, AV: Average, OP: Quasi-Peak)

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant.Fac. [dB/m]	Loss [dB]	Gain [dB]	Distance Factor [dB]	Result [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Height [cm]	Angle [deg]	Remark
Hori.	101.678	QP	48.17	9.95	7.47	32.14	0.00	33.45	43.50	10.0	306	275	
Hori.	108.000	QP	55.06	10.85	7.40	32.13	0.00	41.18	43.50	2.3	309	283	
Hori.	144.000	QP	50.13	14.33	7.81	32.10	0.00	40.17	43.50	3.3	213	78	
Hori.	216.000	QP	44.78	16.52	8.22	32.03	0.00	37.49	43.50	6.0	170	250	
Hori.	661.515	QP	44.29	19.74	10.23	31.92	0.00	42.34	46.00	3.6	179	210	
Hori.	1984.407	PK	53.51	27.17	13.35	37.25	2.24	59.02	73.90	14.8	168	36	
Hori.	2390.000	PK	46.04	27.71	13.70	37.06	2.24	52.63	73.90	21.2	177	249	
Hori.	2396.881	PK	58.98	27.72	13.71	37.05	2.24	65.60	73.90	8.3	177	249	
Hori.	3307.598	PK	50.53	28.27	5.46	36.80	2.24	49.70	73.90	24.2	100	105	
Hori.	4804.000	PK	50.95	31.43	5.92	37.12	2.24	53.42	73.90	20.4	100	264	
Hori.	7206.000	PK	45.57	36.90	7.23	37.84	2.24	54.10	73.90	19.8	100	0	
Hori.	9608.000	PK	45.14	37.94	7.85	39.13	2.24	54.04	73.90	19.8	100	0	
Hori.	1984.407	AV	38.62	27.17	13.35	37.25	2.24	44.13	53.90	9.7	168	36	
Hori.	2390.000	AV	30.05	27.71	13.70	37.06	2.24	36.64	53.90	17.2	177	249	
Hori.	2396.881	AV	32.43	27.72	13.71	37.05	2.24	39.05	53.90	14.8	177	249	
Hori.	3307.598	AV	36.03	28.27	5.46	36.80	2.24	35.20	53.90	18.7	100	105	
Hori.	4804.000	AV	43.27	31.43	5.92	37.12	2.24	45.74	53.90	8.1	100	264	
Hori.	7206.000	AV	32.64	36.90	7.23	37.84	2.24	41.17	53.90	12.7	100	0	
Hori.	9608.000	AV	33.74	37.94	7.85	39.13	2.24	42.64	53.90	11.2	100	0	
Vert.	66.026	QP	46.55	6.44	6.69	32.16	0.00	27.52	40.00	12.4	100	184	
Vert.	72.000	QP	46.74	5.87	7.10	32.16	0.00	27.55	40.00	12.4	100	154	
Vert.	108.000	QP	51.29	10.85	7.40	32.13	0.00	37.41	43.50	6.0	100	88	
Vert.	144.000	QP	50.32	14.33	7.81	32.10	0.00	40.36	43.50	3.1	100	175	
Vert.	891.000	QP	37.07	22.20	10.98	31.10	0.00	39.15	46.00	6.8	100	358	
Vert.	1984.546	PK	54.63	27.17	13.35	37.25	2.24	60.14	73.90	13.7	100	30	
Vert.	2390.000	PK	52.06	27.71	13.70	37.06	2.24	58.65	73.90	15.2	188	156	
Vert.	2398.243	PK	65.03	27.72	13.71	37.05	2.24	71.65	73.90	2.2	188	156	
Vert.	3307.622	PK	54.29	28.27	5.46	36.80	2.24	53.46	73.90	20.4	145	310	
Vert.	4804.000	PK	52.15	31.43	5.92	37.12	2.24	54.62	73.90	19.2	161	118	
Vert.	7206.000	PK	44.52	36.90	7.23	37.84	2.24	53.05	73.90	20.8	100	0	
Vert.	9608.000	PK	46.85	37.94	7.85	39.13	2.24	55.75	73.90	18.1	100	0	
Vert.	1984.546	AV	39.56	27.17	13.35	37.25	2.24	45.07	53.90	8.8	100	30	
Vert.	2390.000	AV	30.44	27.71	13.70	37.06	2.24	37.03	53.90	16.8	188	156	
Vert.	2398.243	AV	32.25	27.72	13.71	37.05	2.24	38.87	53.90	15.0	188	156	
Vert.	3307.622	AV	39.78	28.27	5.46	36.80	2.24	38.95	53.90	14.9	145	310	
Vert.	4804.000	AV	44.74	31.43	5.92	37.12	2.24	47.21	53.90	6.6	161	118	
Vert.	7206.000	AV	32.69	36.90	7.23	37.84	2.24	41.22	53.90	12.6	100	0	
Vert.	9608.000	AV	33.79	37.94	7.85	39.13	2.24	42.69	53.90	11.2	100	0	

Result = Reading + Ant.Fac. + Loss (Cable+(Attenuator or Filter)(below 18 GHz)) - Gain(Amplifier) + Distance factor

Distance factor : 1 GHz - 13 GHz : 20log (3.88 m / 3.0 m) = 2.24 dB

13 GHz - 40 GHz : 20log (1.0 m / 3.0 m) = -9.54 dB

\* These results have sufficient margin without taking account Dwell time factor.

### 20 dBc Data Sheet (RBW 100 kHz, VBW 300 kHz)

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant.Fac. [dB/m]	Loss [dB]	Gain [dB]	Distance Factor [dB]	Result [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
Hori.	2402.000	PK	82.53	27.72	13.71	37.05	2.24	89.15	-	-	Carrier
Hori.	2400.000	PK	41.52	27.72	13.71	37.05	2.24	48.14	69.15	21.0	
Vert.	2402.000	PK	89.84	27.72	13.71	37.05	2.24	96.46	-	-	Carrier
Vert.	2400.000	PK	46.91	27.72	13.71	37.05	2.24	53.53	76.46	22.9	

Result = Reading + Ant.Fac. + Loss (Cable+(Attenuator or Filter)(below 18 GHz)) - Gain(Amplifier) + Distance factor

Distance factor : 1 GHz - 13 GHz : 20log (3.88 m / 3.0 m) = 2.24 dB

13 GHz - 40 GHz : 20log (1.0 m / 3.0 m) = -9.54 dB

**UL Japan, Inc.**

**Shonan EMC Lab.**

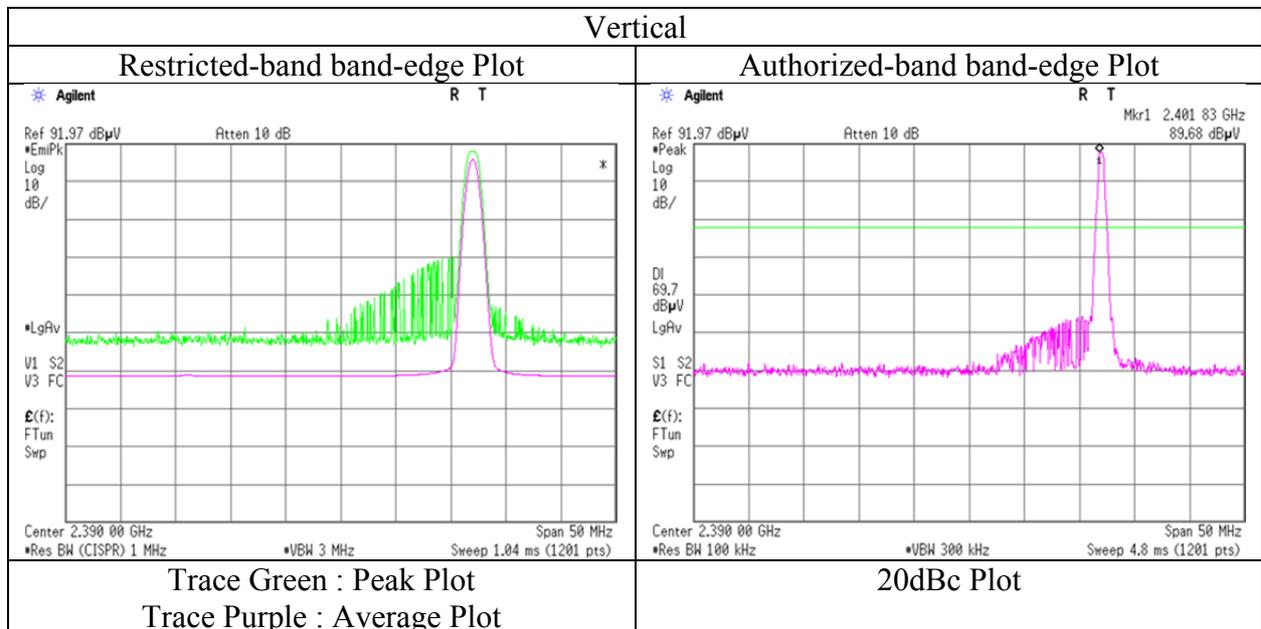
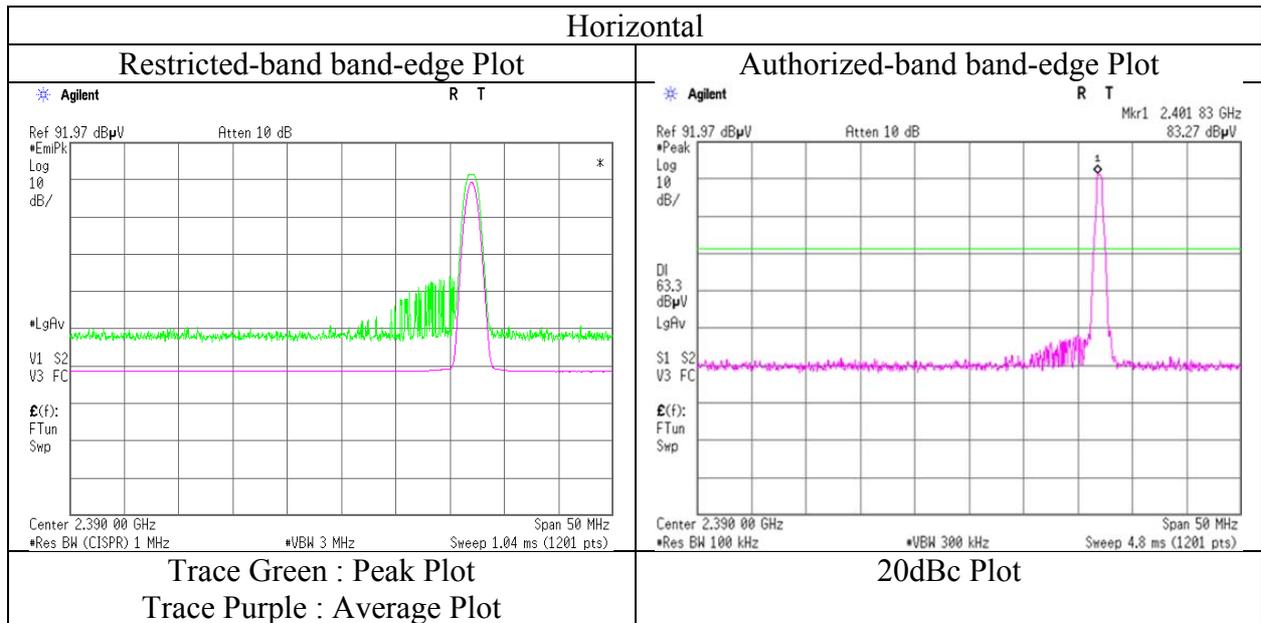
1-22-3 Megumigaoka, Hiratsuka-shi, Kanagawa-ken, 259-1220 JAPAN

Telephone : +81 463 50 6400

Facsimile : +81 463 50 6401

**Radiated Spurious Emission**  
**(Reference Plot for band-edge)**

Test place : Shonan EMC Lab. No.1 Semi Anechoic Chamber  
Report No. : 11413625S-D-R2  
Date : August 17, 2016  
Temperature / Humidity : 23 deg. C / 58 % RH  
Engineer : Takahiro Suzuki  
Mode : Tx, Hopping Off, DH5 2402 MHz



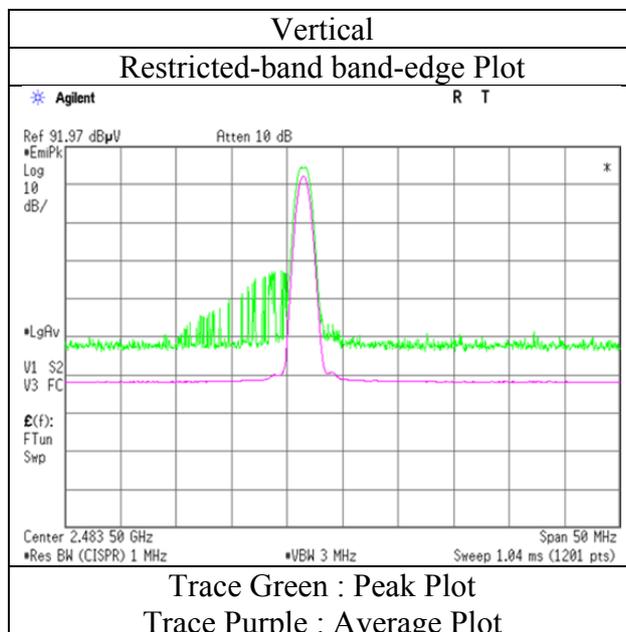
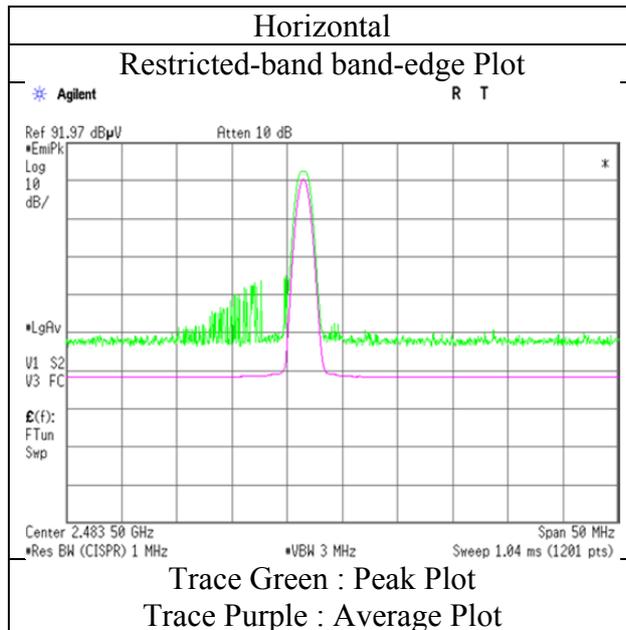
\* Final result of restricted band edge was shown in tabular data.





**Radiated Spurious Emission**  
**(Reference Plot for band-edge)**

Test place : Shonan EMC Lab. No.1 Semi Anechoic Chamber  
Report No. : 11413625S-D-R2  
Date : August 17, 2016  
Temperature / Humidity : 23 deg. C / 58 % RH  
Engineer : Takahiro Suzuki  
Mode : Tx, Hopping Off, DH5 2480 MHz

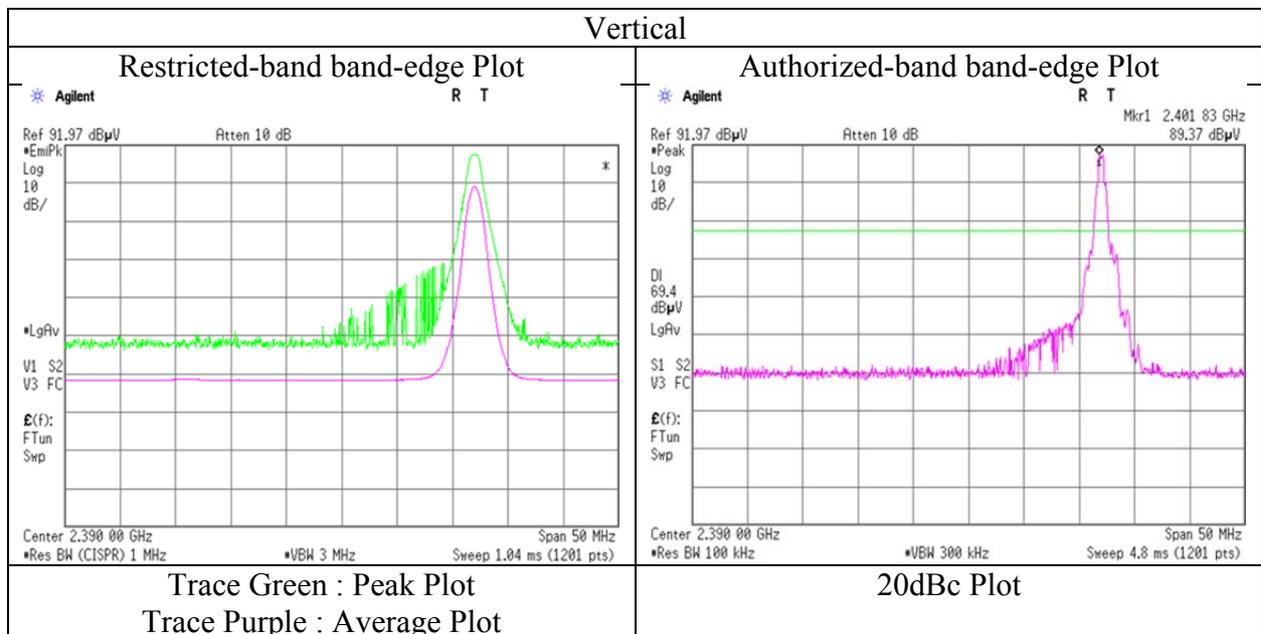
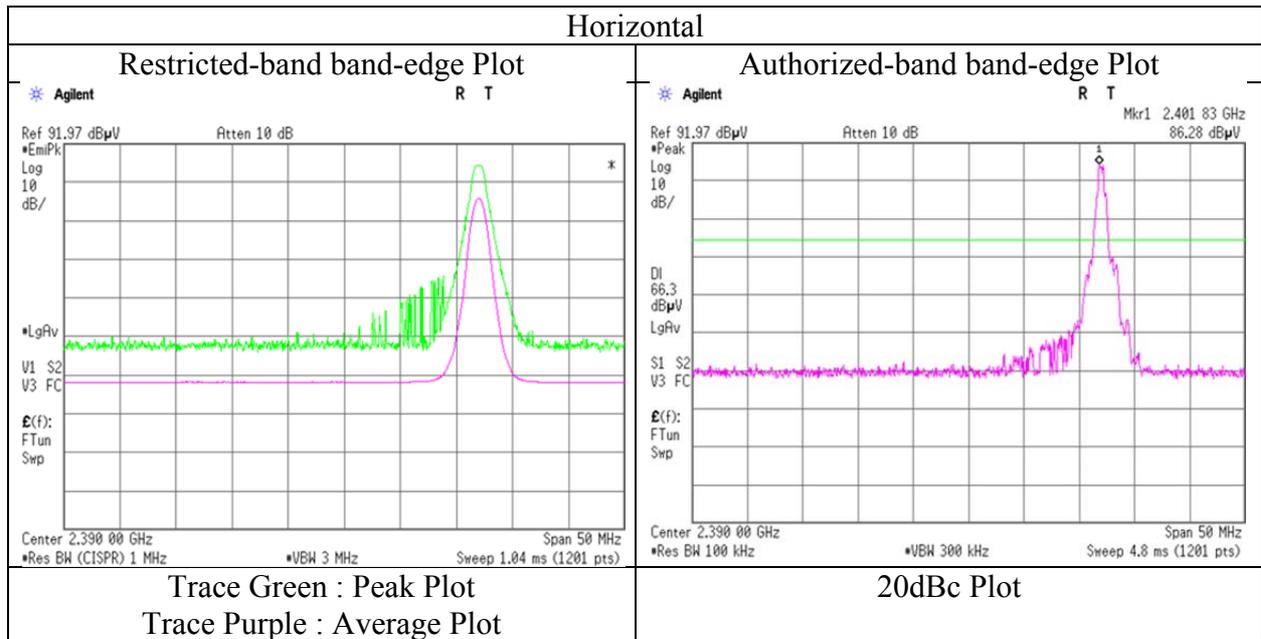


\* Final result of restricted band edge was shown in tabular data.



**Radiated Spurious Emission**  
**(Reference Plot for band-edge)**

Test place : Shonan EMC Lab. No.1 Semi Anechoic Chamber  
Report No. : 11413625S-D-R2  
Date : August 17, 2016  
Temperature / Humidity : 23 deg. C / 58 % RH  
Engineer : Takahiro Suzuki  
Mode : Tx, Hopping Off, 3DH5 2402 MHz



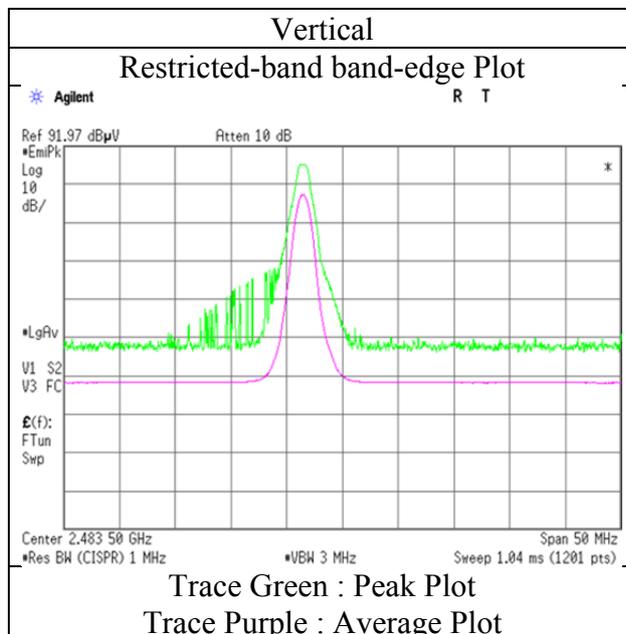
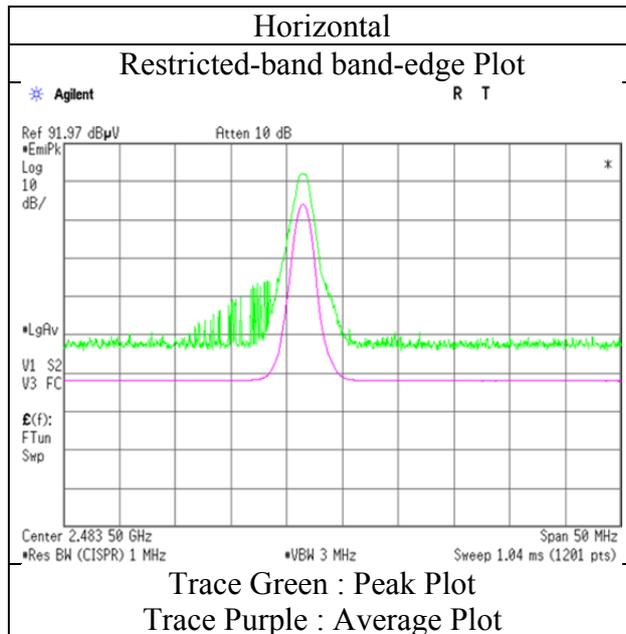
\* Final result of restricted band edge was shown in tabular data.





**Radiated Spurious Emission**  
**(Reference Plot for band-edge)**

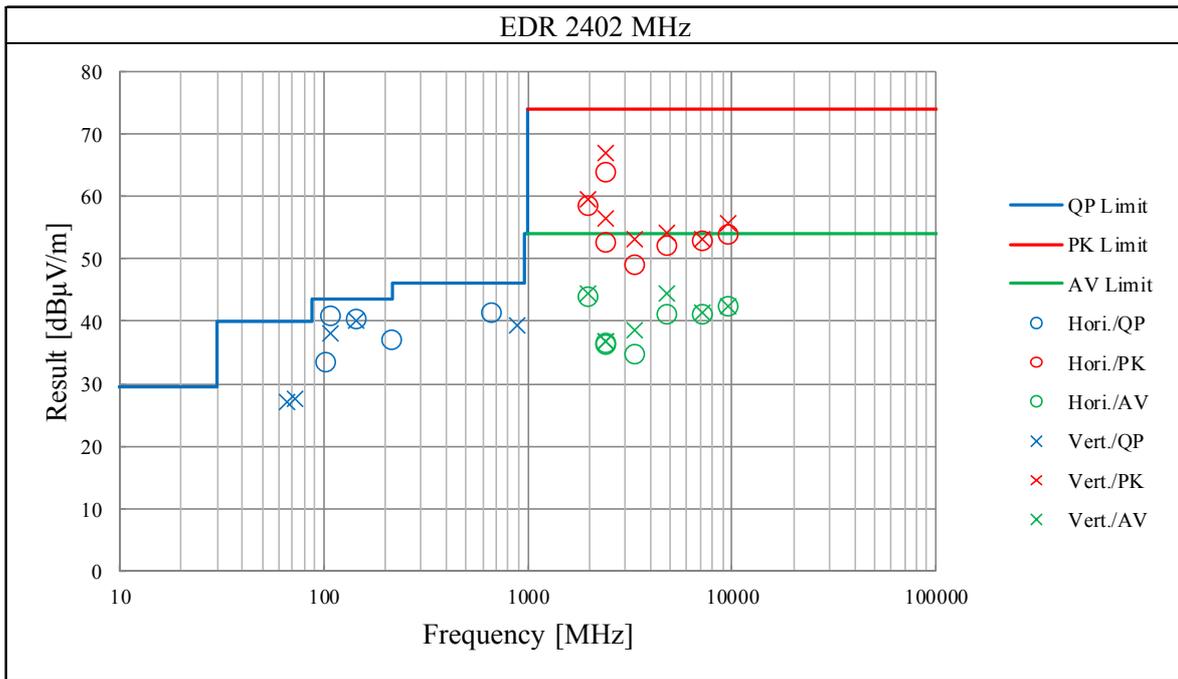
Test place : Shonan EMC Lab. No.1 Semi Anechoic Chamber  
Report No. : 11413625S-D-R2  
Date : August 17, 2016  
Temperature / Humidity : 23 deg. C / 58 % RH  
Engineer : Takahiro Suzuki  
Mode : Tx, Hopping Off, 3DH5 2480 MHz



\* Final result of restricted band edge was shown in tabular data.

**Radiated Spurious Emission**  
**(Plot data, Worst case)**

Test place	Shonan EMC Lab. No.1 and No.3 Semi Anechoic Chamber	
Report No.	11413625S-D-R2	
Date	August 17, 2016	August 18, 2016
Temperature / Humidity	23 deg. C / 58 % RH	22 deg. C / 61 % RH
Engineer	Takahiro Suzuki (1-18 GHz)	Takahiro Suzuki (30-1000 MHz) (18-26.5 GHz)
	(No.1SAC)	(No.3SAC)
Mode	Tx, Hopping Off, 3DH5 2402 MHz	

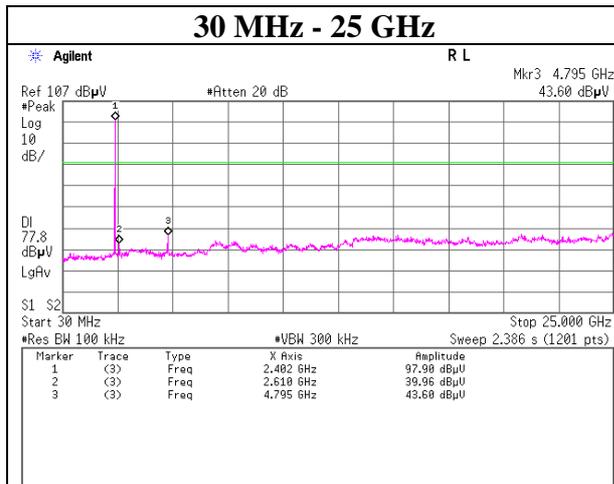
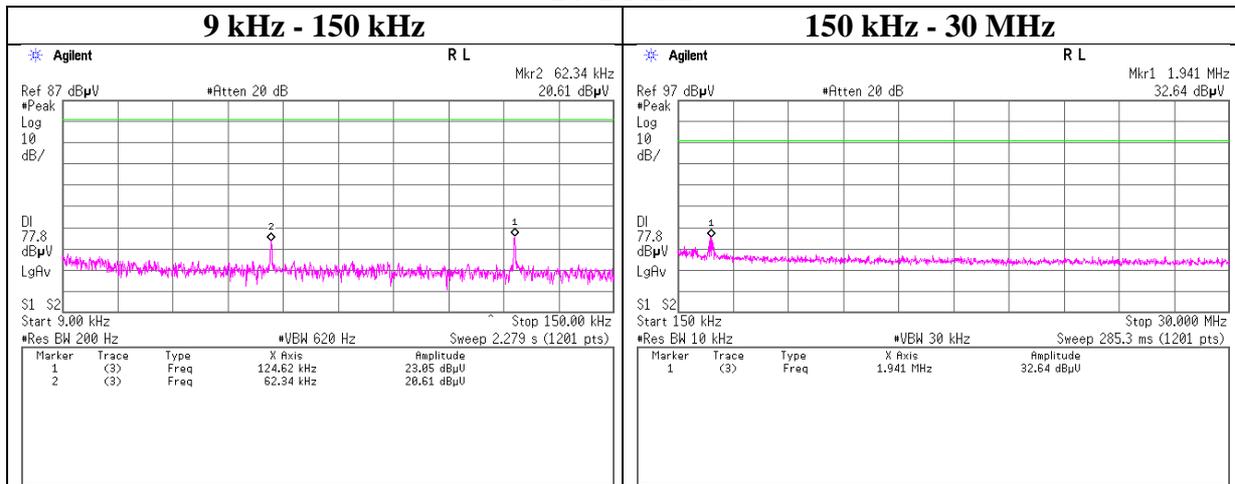


\*These plots data contains sufficient number to show the trend of characteristic features for EUT.

## Conducted Spurious Emission

Test place	Shonan EMC Lab. No.3 Shielded Room
Report No.	11413625S-D-R2
Date	August 22, 2016
Temperature / Humidity	24 deg. C / 52 % RH
Engineer	Kazutaka Takeyama
Mode	Tx, Hopping Off, DH5

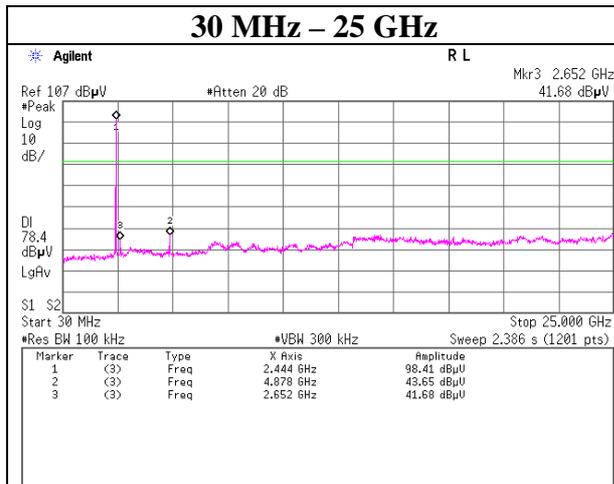
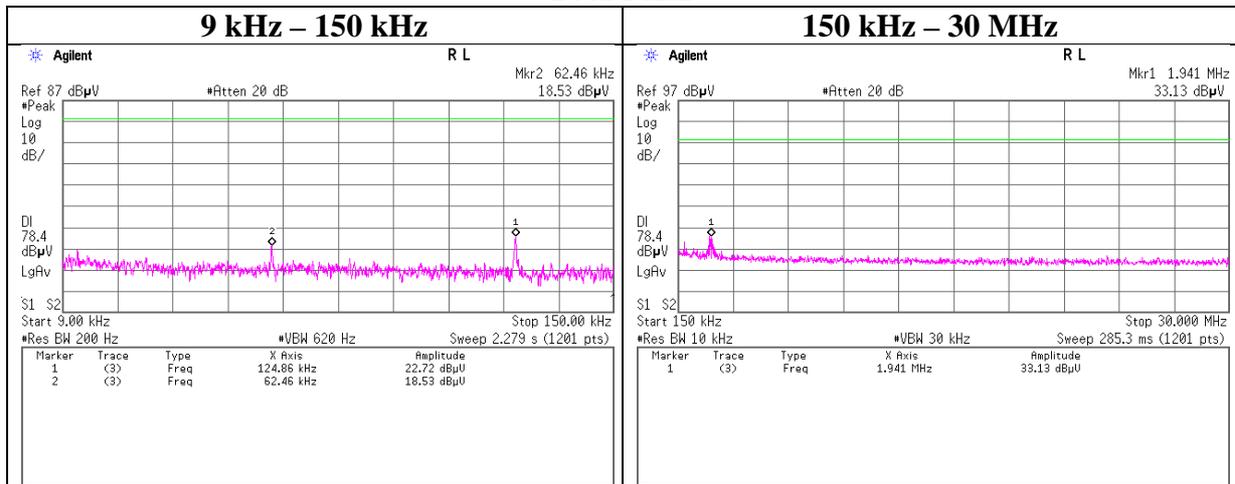
### 2402 MHz



## Conducted Spurious Emission

Test place	Shonan EMC Lab. No.3 Shielded Room
Report No.	11413625S-D-R2
Date	August 22, 2016
Temperature / Humidity	24 deg. C / 52 % RH
Engineer	Kazutaka Takeyama
Mode	Tx, Hopping Off, DH5

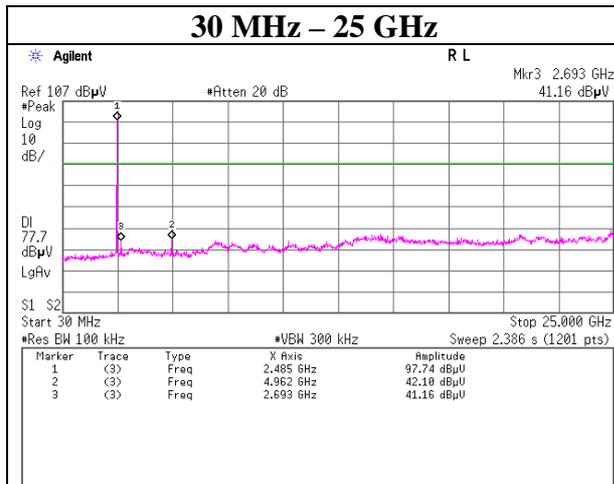
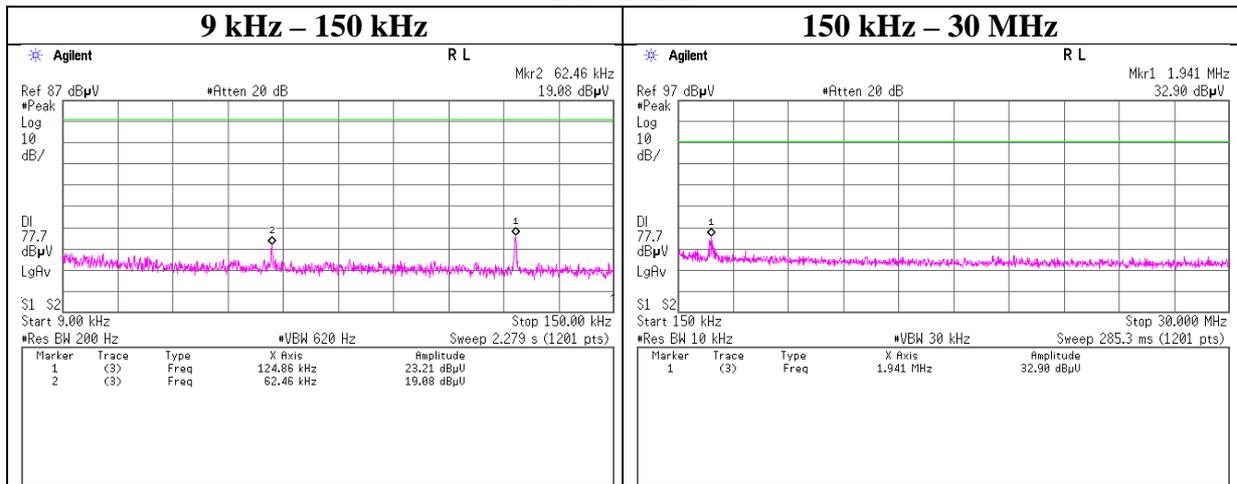
### 2441 MHz



## Conducted Spurious Emission

Test place	Shonan EMC Lab. No.3 Shielded Room
Report No.	11413625S-D-R2
Date	August 22, 2016
Temperature / Humidity	24 deg. C / 52 % RH
Engineer	Kazutaka Takeyama
Mode	Tx, Hopping Off, DH5

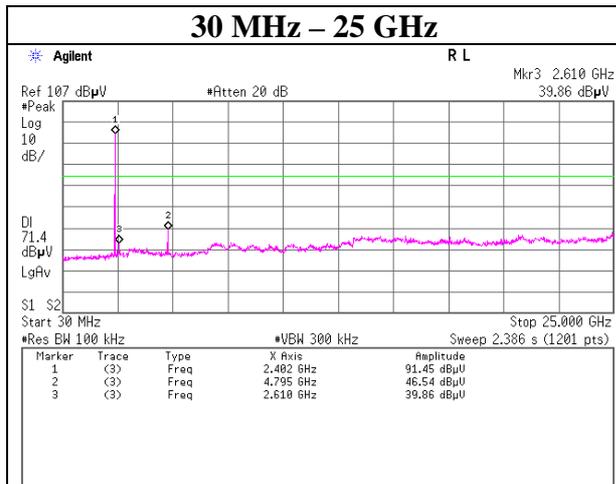
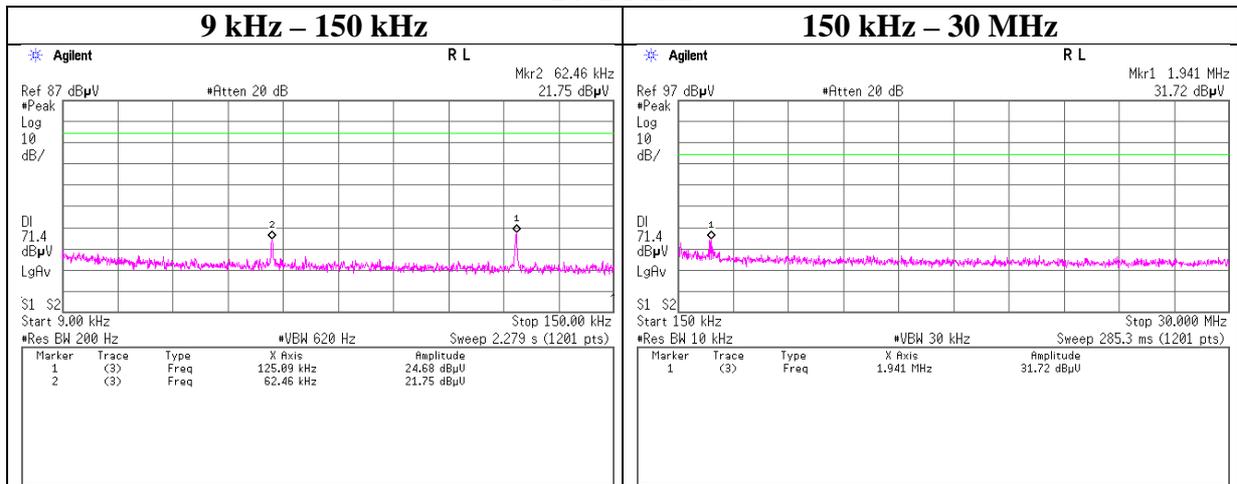
### 2480 MHz



## Conducted Spurious Emission

Test place	Shonan EMC Lab. No.3 Shielded Room
Report No.	11413625S-D-R2
Date	August 22, 2016
Temperature / Humidity	24 deg. C / 52 % RH
Engineer	Kazutaka Takeyama
Mode	Tx, Hopping Off, 3DH5

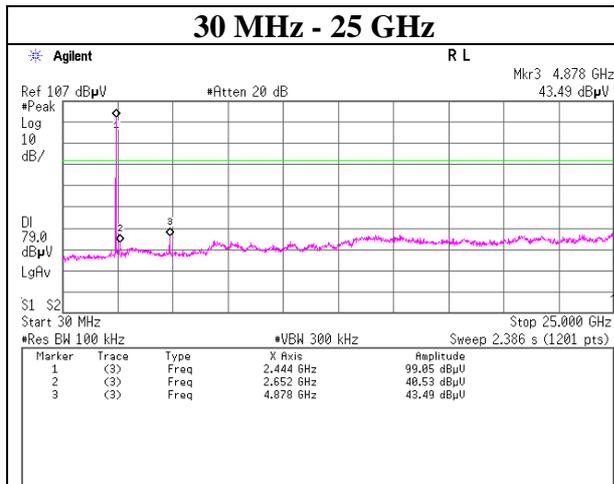
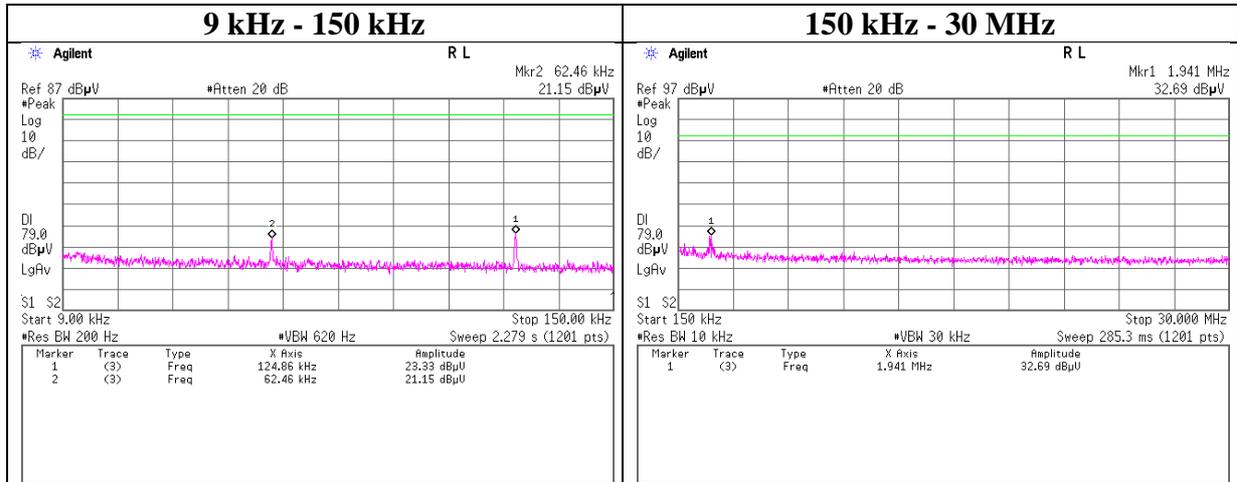
### 2402 MHz



## Conducted Spurious Emission

Test place	Shonan EMC Lab. No.3 Shielded Room
Report No.	11413625S-D-R2
Date	August 22, 2016
Temperature / Humidity	24 deg. C / 52 % RH
Engineer	Kazutaka Takeyama
Mode	Tx, Hopping Off, 3DH5

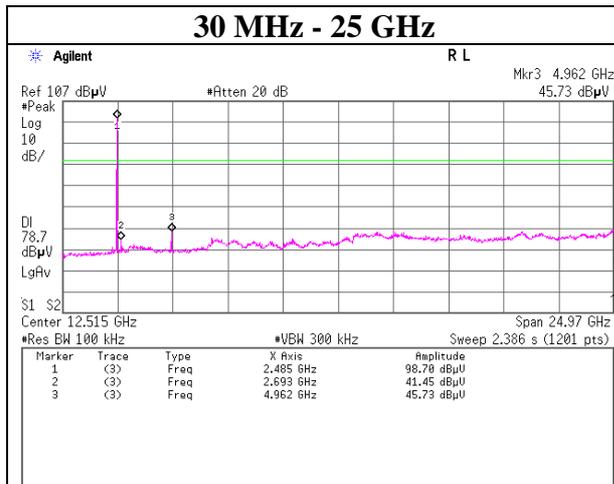
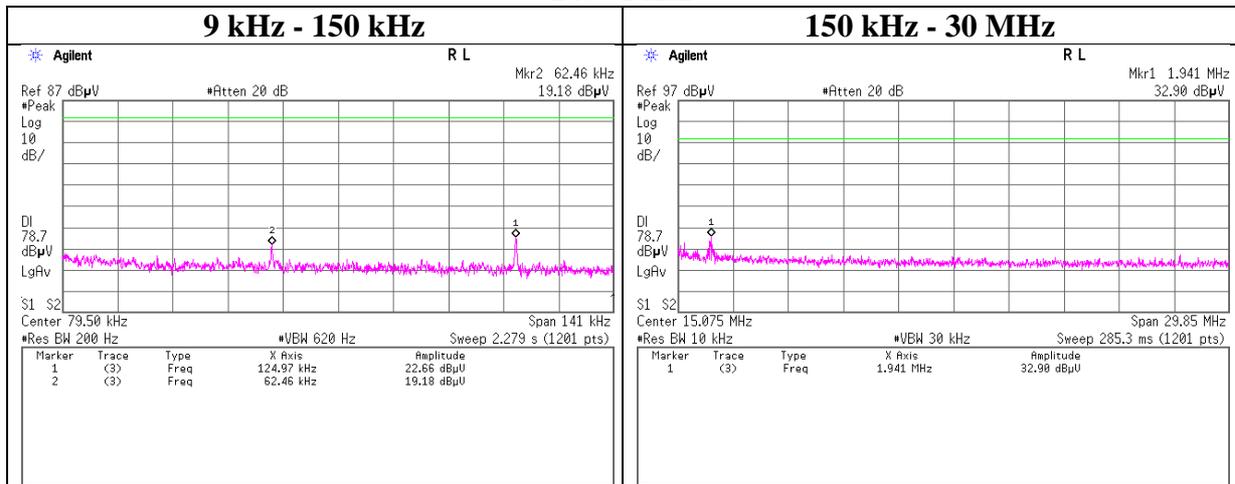
### 2441 MHz



## Conducted Spurious Emission

Test place	Shonan EMC Lab. No.3 Shielded Room
Report No.	11413625S-D-R2
Date	August 22, 2016
Temperature / Humidity	24 deg. C / 52 % RH
Engineer	Kazutaka Takeyama
Mode	Tx, Hopping Off, 3DH5

### 2480 MHz



**UL Japan, Inc.**

**Shonan EMC Lab.**

1-22-3 Megumigaoka, Hiratsuka-shi, Kanagawa-ken, 259-1220 JAPAN

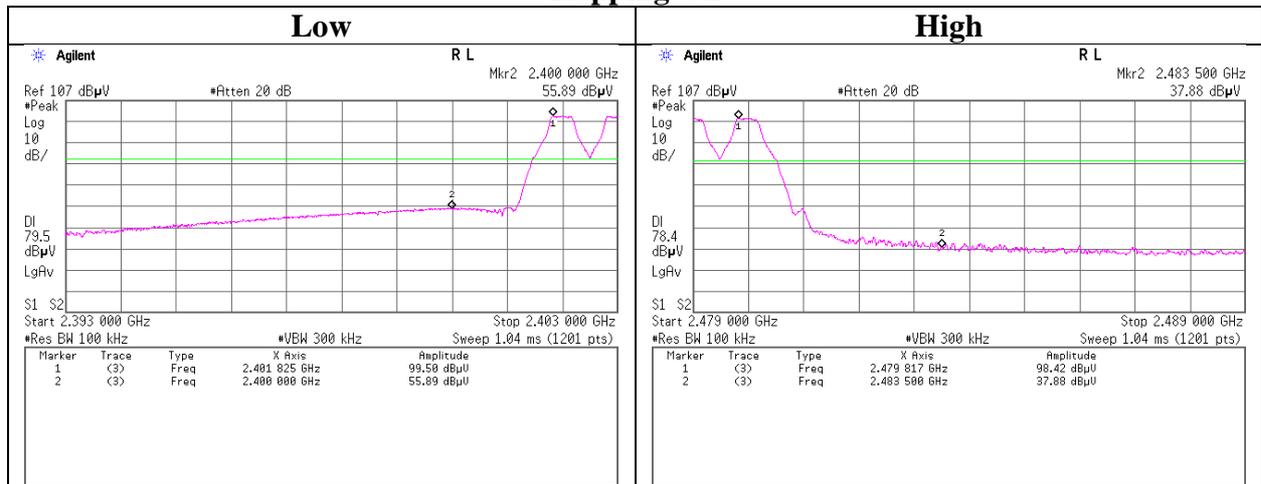
Telephone : +81 463 50 6400

Facsimile : +81 463 50 6401

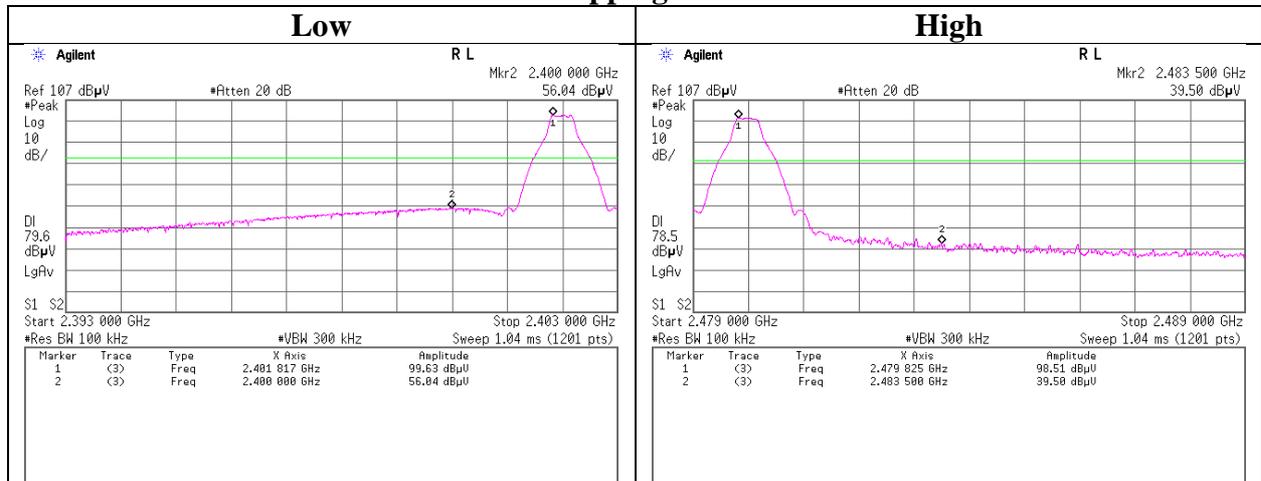
## Conducted Emission Band Edge compliance

Test place	Shonan EMC Lab. No.3 Shielded Room
Report No.	11413625S-D-R2
Date	August 22, 2016
Temperature / Humidity	24 deg. C / 52 % RH
Engineer	Kazutaka Takeyama
Mode	Tx DH5

### Hopping On



### Hopping Off



**UL Japan, Inc.**

**Shonan EMC Lab.**

1-22-3 Megumigaoka, Hiratsuka-shi, Kanagawa-ken, 259-1220 JAPAN

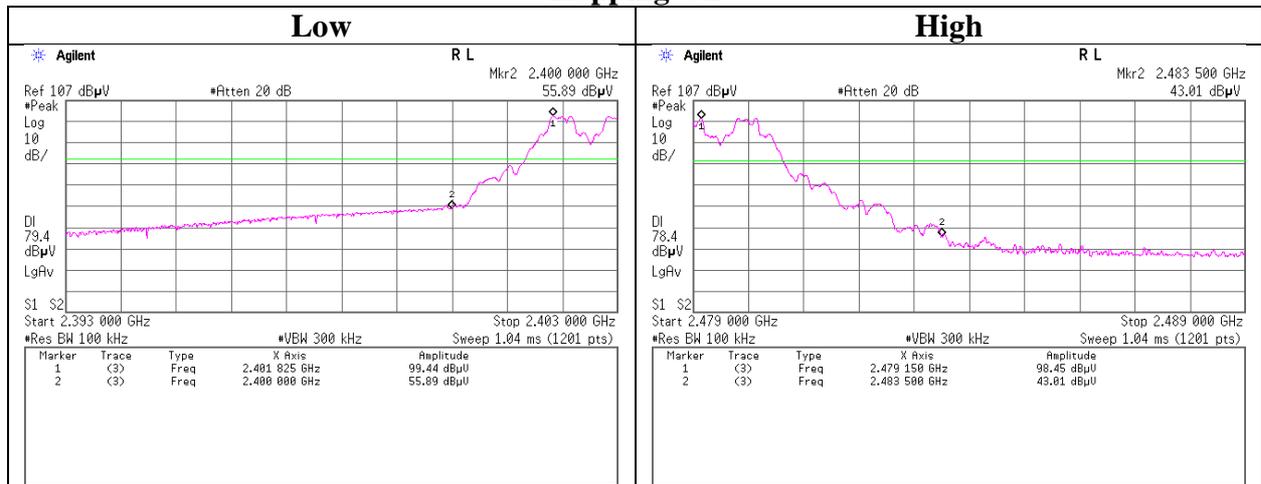
Telephone : +81 463 50 6400

Facsimile : +81 463 50 6401

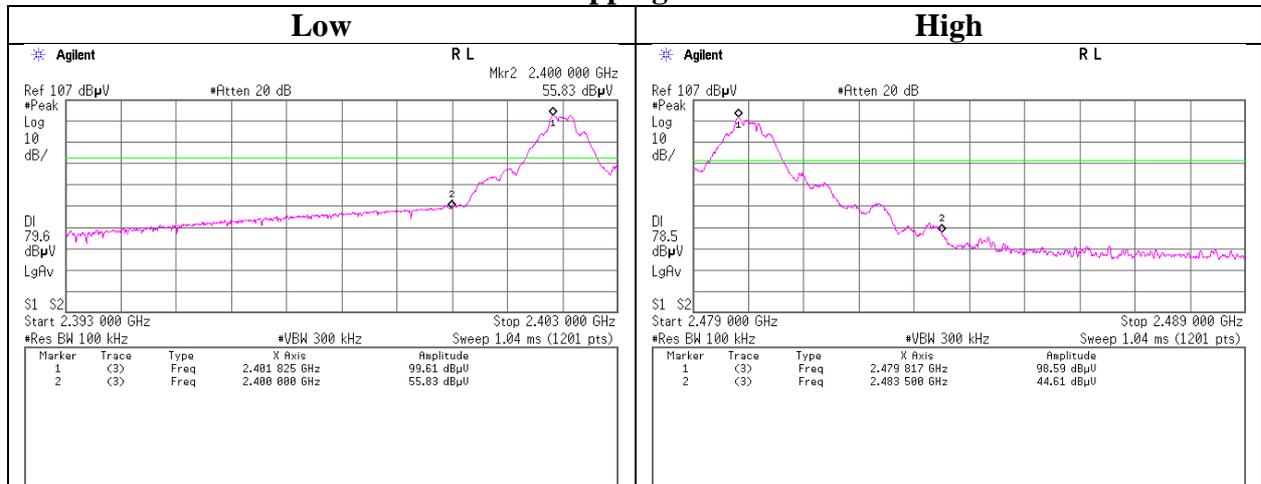
## Conducted Emission Band Edge compliance

Test place	Shonan EMC Lab. No.3 Shielded Room
Report No.	11413625S-D-R2
Date	August 22, 2016
Temperature / Humidity	24 deg. C / 52 % RH
Engineer	Kazutaka Takeyama
Mode	Tx 3DH5

### Hopping On



### Hopping Off



**UL Japan, Inc.**

**Shonan EMC Lab.**

1-22-3 Megumigaoka, Hiratsuka-shi, Kanagawa-ken, 259-1220 JAPAN

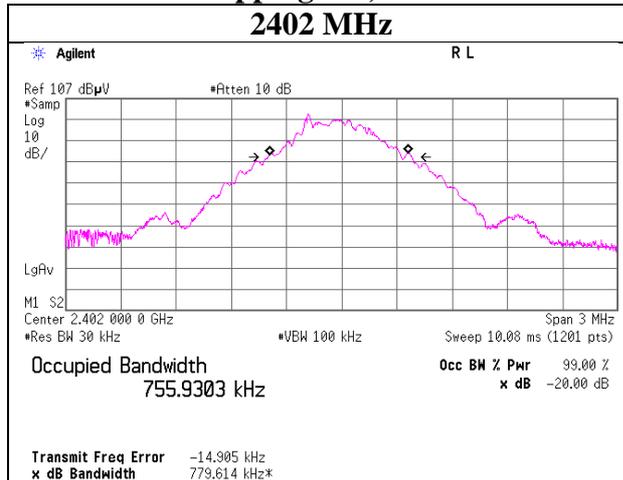
Telephone : +81 463 50 6400

Facsimile : +81 463 50 6401

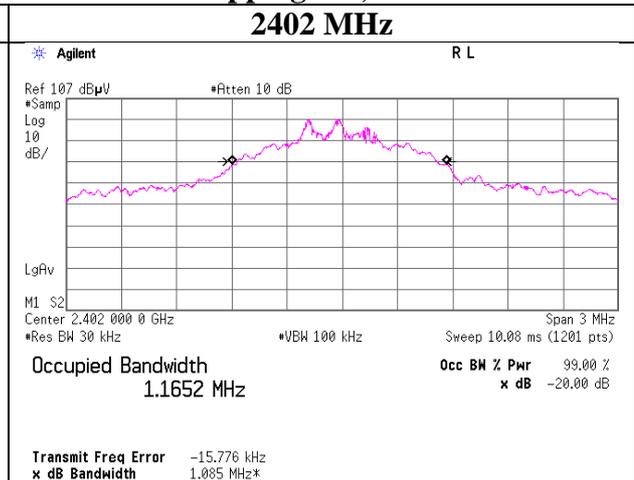
## 99% Occupied Bandwidth

Test place	Shonan EMC Lab. No.3 Shielded Room
Report No.	11413625S-D-R2
Date	August 22, 2016
Temperature / Humidity	24 deg. C / 52 % RH
Engineer	Kazutaka Takeyama
Mode	Tx

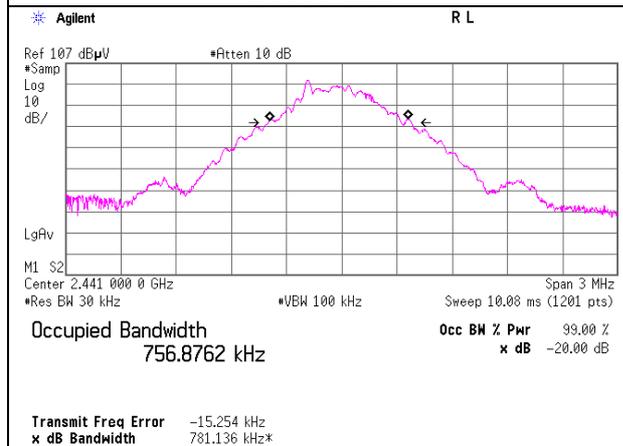
### Hopping Off, DH5



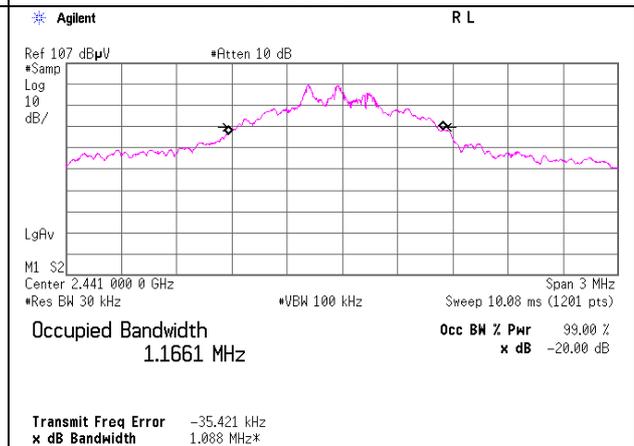
### Hopping Off, 3DH5



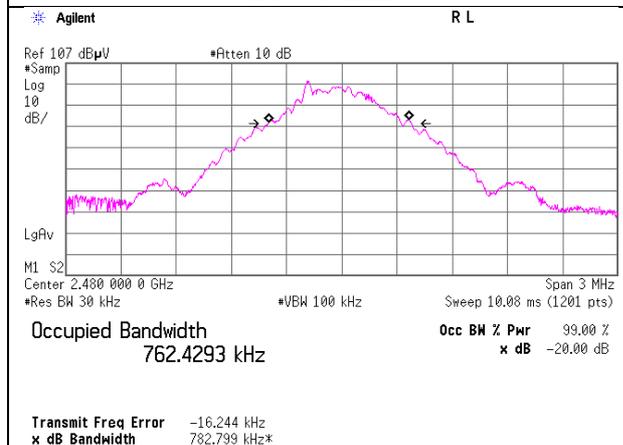
### 2441 MHz



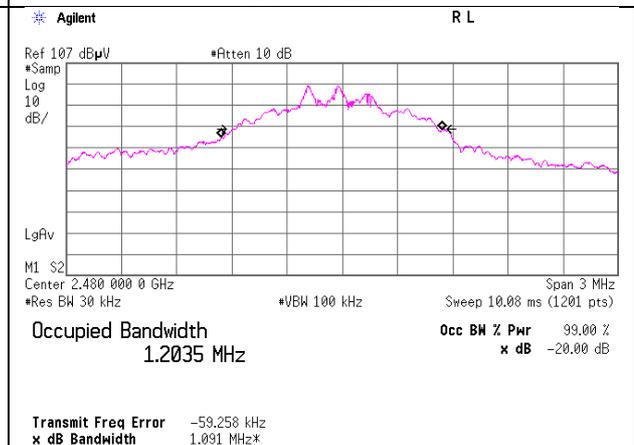
### 2441 MHz



### 2480 MHz



### 2480 MHz



**UL Japan, Inc.**

**Shonan EMC Lab.**

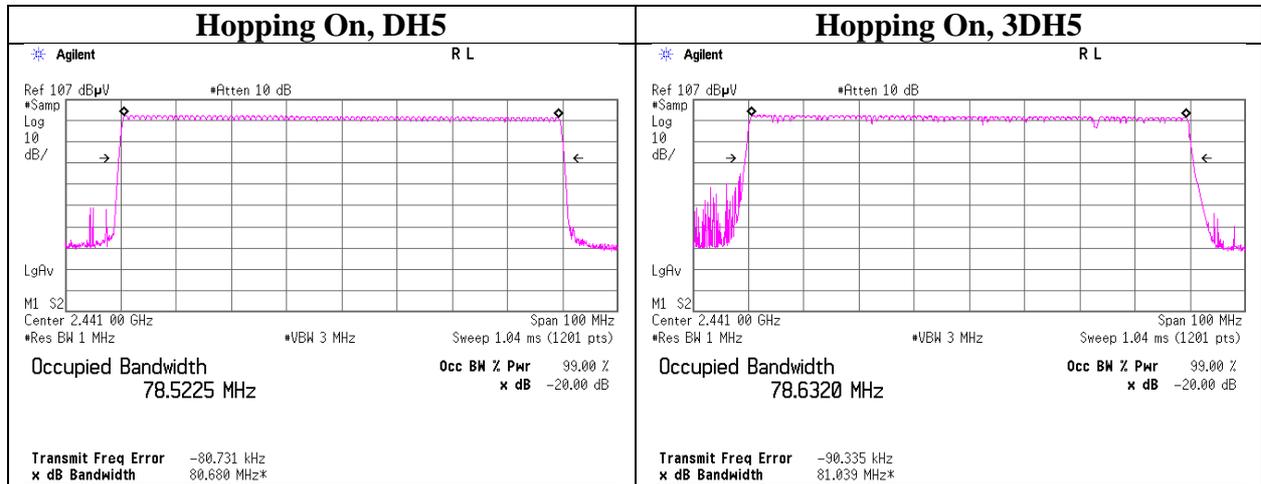
1-22-3 Megumigaoka, Hiratsuka-shi, Kanagawa-ken, 259-1220 JAPAN

Telephone : +81 463 50 6400

Facsimile : +81 463 50 6401

## 99% Occupied Bandwidth

Test place	Shonan EMC Lab. No.3 Shielded Room
Report No.	11413625S-D-R2
Date	August 22, 2016
Temperature / Humidity	24 deg. C / 52 % RH
Engineer	Kazutaka Takeyama
Mode	Tx



## APPENDIX 2: Test instruments

### Test equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
SSA-02	Spectrum Analyzer	Agilent	E4448A	MY48250106	AT	2016/03/23 * 12
SAT10-06	Attenuator	Agilent	8493C-010	74865	AT	2015/11/04 * 12
SCC-G33	Coaxial Cable	Junkosha	MWX241-010 00KMSKMS	-	AT	2016/04/18 * 12
SOS-06	Humidity Indicator	A&D	AD-5681	4062118	AT	2015/12/07 * 12
STS-03	Digital Hitester	Hioki	3805-50	080997823	AT	2015/11/18 * 12
SPM-06	Power Meter	Anritsu	ML2495A	0850009	AT	2016/04/01 * 12
SPSS-03	Power sensor	Anritsu	MA2411B	0917063	AT	2016/04/01 * 12
SSA-01	Spectrum Analyzer	Agilent	N9010A-526	MY48031482	AT	2016/04/28 * 12
KOS-11	Humidity Indicator	Custom	CTH-202	Q.C.13	AT	2015/12/07 * 12
STS-04	Digital Hitester	Hioki	3805-50	080997827	AT	2016/03/22 * 12
SAF-05	Pre Amplifier	TOYO Corporation	TPA0118-36	1440490	RE	2016/02/10 * 12
SCC-G05	Coaxial Cable	Junkosha	J12J102207-0 0	APR-30-15-0 37	RE	2016/05/24 * 12
SCC-G22	Coaxial Cable	Suhner	SUCOFLEX 104	296199/4	RE	2016/05/11 * 12
SHA-RS01	Horn Antenna	Schwarzbeck	BBHA9120D	770	RE	2015/08/11 * 12
SOS-03	Humidity Indicator	A&D	AD-5681	4063325	RE	2015/10/22 * 12
SSA-02	Spectrum Analyzer	Agilent	E4448A	MY48250106	RE	2016/03/23 * 12
SJM-09	Measure	PROMART	SEN1935	-	RE	-
SAEC-02(SV SWR)	Semi-Anechoic Chamber	TDK	SAEC-02(SV SWR)	2	RE	2016/07/22 * 12
COTS-SEMI- 1	EMI Software	TSJ	TEPTO-DV(R E,CE,RFI,MF)	-	RE	-
STS-02	Digital Hitester	Hioki	3805-50	080997819	RE	2016/03/22 * 12
SFL-18	Highpass Filter	MICRO-TRONICS	HPM50111	119	RE	2016/04/18 * 12
SAT10-06	Attenuator	Agilent	8493C-010	74865	RE	2015/11/04 * 12
SAF-08	Pre Amplifier	TOYO Corporation	HAP18-26W	00000019	RE	2016/03/23 * 12
SHA-04	Horn Antenna	ETS LINDGREN	3160-09	LM3640	RE	2016/03/15 * 12
SCC-G33	Coaxial Cable	Junkosha	MWX241-010 00KMSKMS	-	RE	2016/04/18 * 12
SCC-G15	Coaxial Cable	Suhner	SUCOFLEX 102	32703/2	RE	2016/03/08 * 12
SAEC-03(NS A)	Semi-Anechoic Chamber	TDK	SAEC-03(NS A)	3	RE	2016/07/15 * 12
SOS-05	Humidity Indicator	A&D	AD-5681	4062518	RE	2015/10/22 * 12
SJM-15	Measure	ASKUL	-	-	RE	-
STS-03	Digital Hitester	Hioki	3805-50	080997823	RE	2015/11/18 * 12
SBA-03	Biconical Antenna	Schwarzbeck	BBA9106	91032666	RE	2015/10/11 * 12
SLA-03	Logperiodic Antenna	Schwarzbeck	UHALP9108 A	UHALP 9108-A 0901	RE	2015/10/11 * 12
SAT6-08	Attenuator	HIROSE ELECTRIC CO.,LTD.	AT-406(40)	-	RE	2016/08/04 * 12
SCC-C1/C2/C 3/C4/C5/C10/ SRSE-03	Coaxial Cable&RF Selector	Fujikura/Fujikura/Su hner/Suhner/Suhner/Su hner/TOYO	8D2W/12DSF A/141PE/141P E/141PE/141P E/NS4906	-/0901-271(R F Selector)	RE	2016/04/22 * 12
SAF-03	Pre Amplifier	SONOMA	310N	290213	RE	2016/02/25 * 12
STR-06	Test Receiver	Rohde & Schwarz	ESCI	101259	RE	2016/03/28 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item: RE: Radiated Emission test, AT: Antenna Terminal Conducted test

UL Japan, Inc.

Shonan EMC Lab.

1-22-3 Megumigaoka, Hiratsuka-shi, Kanagawa-ken, 259-1220 JAPAN

Telephone : +81 463 50 6400

Facsimile : +81 463 50 6401